

TOTAL DOSE RADIATION TEST REPORT

Part Type : BA20
Package : TO-03
Description : Transistors - High power NPN
Manufacturer : STMicroelectronics
Date Code: NA

Top-Rel Purchase Order N° 5503571 dated 03/26/2010

Top-Rel Technical Responsible: Alessandro Cavagnoli

Hirex reference :	HRX/TID/0772	Issue : 01	Date :	March 31 st , 2010
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Hirex Engineering	Total Dose Radiation Test Report		Ref.:	HRX/TID/0772
	BA20	STMicroelectronics	Issue:	01

**TOTAL DOSE RADIATION TEST REPORT
on BA20
STMicroelectronics
Transistors - High power NPN**

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1 Introduction

A total dose radiation verification test of the STMicroelectronics BA20, Transistors - High power NPN has been performed with an accumulated dose of about 109 Krad(Si) at a dose rate of 275 rad(Si)/hour, in response to Top-Rel purchase order reference 5503571.

The purpose of this test was to evaluate total dose withstanding of this component, to investigate its suitability for being used in space applications. This test was conducted on samples provided by Top-Rel. Test has been performed in accordance with Hirex Engineering proposal reference HRX/PRO/2906 Issue 01 dated 09/12/2009.

A complete set of electrical measurements together with graphical representation of measured parameters with respect to total dose received, are provided for all samples.

2 Applicable and Reference Documents

2.1 Applicable Documents

- Hirex Engineering proposal: HRX/PRO/2906 Issue 01 dated 09/12/2009
- Top-Rel specification: TPR/PL/STM/1153 issue 01 dated 12/17/2009.

2.2 Reference Documents

- Manufacturer Datasheet

3 Test Samples

7 samples of the BA20 device were tested (6 ON + 1 control sample).

Samples were allocated into the bias conditions during exposures and annealing as provided in the following table.

Serial Number	Allocation
1	Control
2	Biased ON
3	Biased ON
4	Biased ON
5	Biased ON
6	Biased ON
7	Biased ON

Identification of the BA20 is given below:

Part Number: BA20

Top Marking: manuscript BA20 serial

Diffusion Lot:

Date Code: NA

4 Experimental Conditions

4.1 Radiation Source Dose Rate and Annealing

The dose exposures were performed at ENEA in the Calliope plant located at the CASACCIA research centre in ROME (Italy).

The γ irradiation plant is a pool-type irradiation facility equipped with a ^{60}Co gamma source in a large shielded panoramic room. The storage water pool, that houses the source, has dimensions of $2 \times 4.4 \times 8 \text{ m}^3$. The emitted radiation has two photons of 1.173 and 1.332 MeV working in coincidence with a mean photon's energy of 1.25 MeV.

It is possible to vary the dose rate by simply adjusting the distance of devices under test to the source in a range of a few rad/H up to 2 Mrad/H.

The main Calliope features are reported in the table and Figure 1 below.

Source:	^{60}Co
Geometry:	Cylindrical rack with radioisotope pencils placed on two levels of external rack surface
Emitted radiation:	2 γ photons emitted in coincidence
Photons Energy:	1.173 and 1.332 MeV (average 1.25 MeV)
Max licensed activity:	$3.7 \times 10^{15} \text{ Bq}$ (100 kCi)
Dose rate range:	Few rad/h up to 2 Mrad/h

Table 1 : Calliope main features

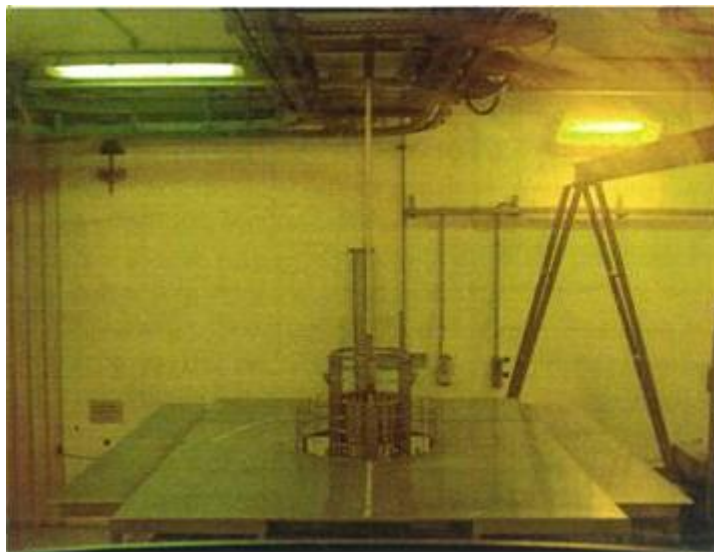


Figure 1 : View of the ^{60}Co γ source through the yellow lead window of the control room

The irradiation conditions used for this test are provided in the following table:

Irradiation Steps	Dose rate	Annealing steps	Temperature
krads	krads/h	Hours	°C
0			
26.3	0.275		Room
52.2	0.275		Room
78.1	0.275		Room
108.6	0.275		Room
		24	Room
		168	100

4.2 Bias during Dose Exposures and Measurements conditions

4.2.1 Bias conditions

During exposures test board allowed to bias 6 samples in accordance with the electrical circuit provided in Figure 1.

During annealing steps the same stress conditions were applied at room and 100°C temperatures.

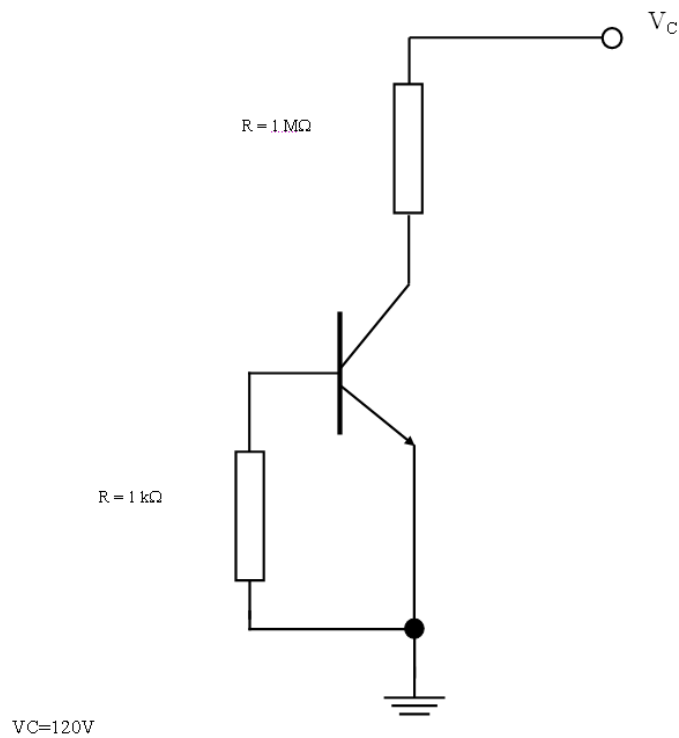


Figure 2 : Bias Conditions during Irradiation Exposures and Annealing

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4.2.2 Electrical Measurements

Electrical parameters test program principle for BA20 is provided in Figure 2.

One HP4142 DC tester and a TEK371A curve tracer were used to perform required measurements.

A dedicated test fixture was designed to ensure proper measurement conditions. In addition a faraday cage was used to ensure optimum conditions for low level measurements.

Test results were automatically loaded in an Excel worksheet and compared in real time to specification limits. This allowed for real time data analysis in particular when failures were recorded.

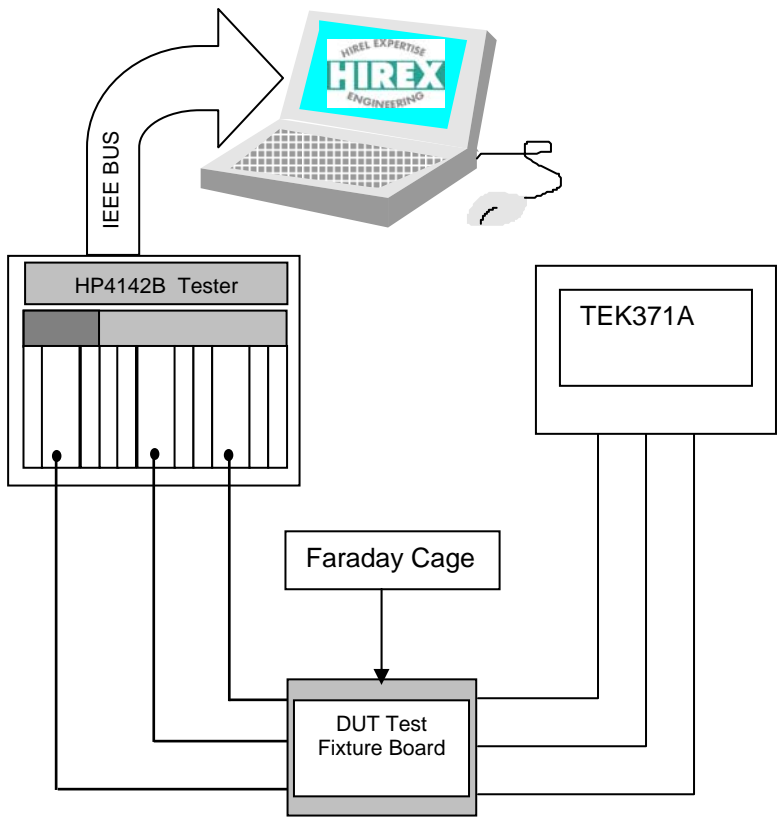


Figure 3 : BA20 test program principle

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Electrical parameters test conditions and limits used for performing this test are given in the following table.

PARAMETERS	SYMBOLS	TEST CONDITIONS	MIN	MAX	UNITS
Collector emitter voltage base open	V_{ceo}	I _c = 200mA	120	-	V
Collector emitter cut off current	I_{ceo}	V _{cb} = 80V	-	10.0E-03	A
Emitter base cut off current	I_{ebo}	V _{eb} = 7V	-	10.0E-03	A
Forward current transfer ratio 1	h_{fe1}	V _{ce} = 2V I _c = 100μA	1	-	-
Forward current transfer ratio 2	h_{fe2}	V _{ce} = 2V I _c = 1mA	10	-	-
Forward current transfer ratio 3	h_{fe3}	V _{ce} = 2V I _c = 10mA	10	-	-
Forward current transfer ratio 4	h_{fe4}	V _{ce} = 2V I _c = 100mA	10	-	-
Forward current transfer ratio 5	h_{fe5}	V _{ce} = 2V I _c = 500mA	10	-	-
Forward current transfer ratio 6	h_{fe6}	V _{ce} = 2V I _c = 1A	10	-	-
Forward current transfer ratio 7	h_{fe7}	V _{ce} = 2V I _c = 2A	10	-	-
Forward current transfer ratio 8	h_{fe8}	V _{ce} = 2V I _c = 4A	10	-	-
Forward current transfer ratio 9	h_{fe9}	V _{ce} = 2V I _c = 6A	10	-	-
Forward current transfer ratio 9	h_{fe10}	V _{ce} = 2V I _c = 8A	1	-	-
Forward current transfer ratio 9	h_{fe11}	V _{ce} = 2V I _c = 10A	1	-	-
Forward current transfer ratio 9	h_{fe12}	V _{ce} = 2V I _c = 15A	20	100	-
Forward current transfer ratio 9	h_{fe13}	V _{ce} = 2V I _c = 20A	20	-	-
Collector emitter saturation voltage	V_{ce(sat)1}	I _c = 1A I _b = 100mA	-	1.5	V
Collector emitter saturation voltage	V_{ce(sat)2}	I _c = 2A I _b = 200mA	-	1.5	V
Collector emitter saturation voltage	V_{ce(sat)3}	I _c = 15A I _b = 1.2A	-	0.75	V
Base emitter saturation voltage	V_{be(sat)1}	I _c = 1A I _b = 100mA	-	1.5	V
Base emitter saturation voltage	V_{be(sat)2}	I _c = 2A I _b = 200mA	-	1.5	V
Base emitter saturation voltage	V_{be(sat)3}	I _c = 15A I _b = 1.2A	-	1.5	V
Base emitter voltage	V_{be1}	I _c = 100μA V _{ce} = 2V	-	1.5	V
Base emitter voltage	V_{be2}	I _c = 1mA V _{ce} = 2V	-	1.5	V
Base emitter voltage	V_{be3}	I _c = 10mA V _{ce} = 2V	-	1.5	V
Base emitter voltage	V_{be4}	I _c = 100mA V _{ce} = 2V	-	1.5	V
Base emitter voltage	V_{be5}	I _c = 500mA V _{ce} = 2V	-	1.5	V
Base emitter voltage	V_{be6}	I _c = 1A V _{ce} = 2V	-	1.5	V

PARAMETERS	SYMBOLS	TEST CONDITIONS	MIN	MAX	UNITS
Base emitter voltage	Vbe7	Ic = 2A Vce = 2V	-	1.5	V
Base emitter voltage	Vbe8	Ic = 4A Vce = 2V	-	1.5	V
Base emitter voltage	Vbe9	Ic = 6A Vce = 2V	-	1.5	V
Base emitter voltage	Vbe10	Ic = 8A Vce = 2V	-	1.5	V
Base emitter voltage	Vbe11	Ic = 15A Vce = 2V	-	1.6	V

Table 2 : Measured electrical parameters

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5 Conclusion

A Total Ionizing Dose verification test was carried out by Hirex Engineering under Top-Rel contract on the STMicroelectronics BA20 Transistors - High power NPN in TO-03 package. 6 samples plus one control sample were used during testing. They were exposed to radiation using a dose rate of 275 rad(Si)/hour at room temperature.

All parameters remained within specification limits all along testing.

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6 Test Results

Test results including tables and graphics are provided in this section for each measured parameter.

Failed values with respect to specified limits are highlighted in bold red font in the tables.

Post irradiation values are calculated using 3σ approach.

- For positive variation $(X)_{\text{LOT+}} = \text{mean}(X) + 3 \times \sigma(X)$
- For negative variation $(X)_{\text{LOT-}} = \text{mean}(X) - 3 \times \sigma(X)$
- $(X)_{\text{LOT WORST CASE}} = \text{Worstcase}((X)_{\text{LOT+}}, (X)_{\text{LOT-}})$

Post irradiation parameters drifts (noted ΔX) are defined as follows:

$$\Delta X = X_{\text{post rad}} - X_{\text{initial}}$$

Where $X_{\text{post rad}}$ stands for the value of X after irradiation (at 50krads (Si), 70krads (Si) or 100krads (Si)) and X_{initial} stands for the pre-irradiation value of X.

Post irradiation drift values are calculated using 3σ approach.

- For positive variation $\Delta(X)_{\text{LOT+}} = \text{mean}(\Delta X) + 3 \times \sigma(\Delta X)$
- For negative variation $\Delta(X)_{\text{LOT-}} = \text{mean}(\Delta X) - 3 \times \sigma(\Delta X)$
- $\Delta(X)_{\text{LOT WORST CASE}} = \text{Worstcase}(\Delta(X)_{\text{LOT+}}, \Delta(X)_{\text{LOT-}})$

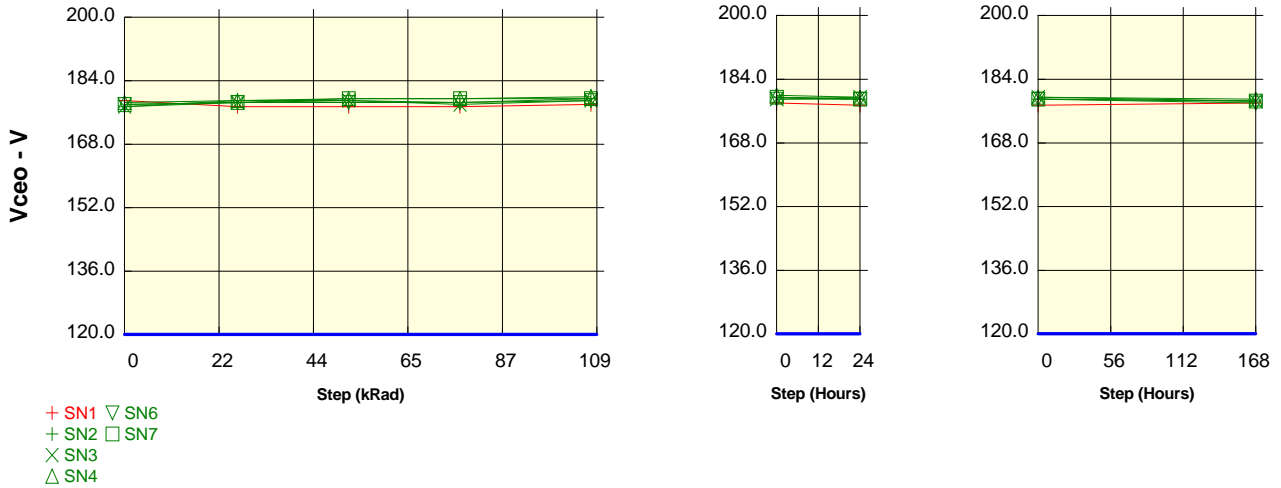
For bipolar transistors, drifts on forward current transfer ratio are calculated as follows:

$$\Delta\left(\frac{1}{h_{FE}}\right)_{\text{LOT}} = \text{mean}\left(\Delta\frac{1}{h_{FE}}\right) + 3 \times \sigma\left(\Delta\frac{1}{h_{FE}}\right)$$

$$[h_{FE}]_{\text{POST RAD}} = \frac{1}{\Delta\left(\frac{1}{h_{FE}}\right)_{\text{LOT}} + \frac{1}{h_{FE(\text{min})}}}$$

Where σ stands for standard deviation and $h_{FE(\text{min})}$ stands for the pre-irradiation spec minimum h_{FE} limit available in table 2.

Test conditions : TID
Parameter : Collector to Emitter Voltage Base Open : Vceo
Ic = 200mA
 Unit : V
 Spec Limit Min : 120.0
 Spec limits are represented in bold lines on the graphic.



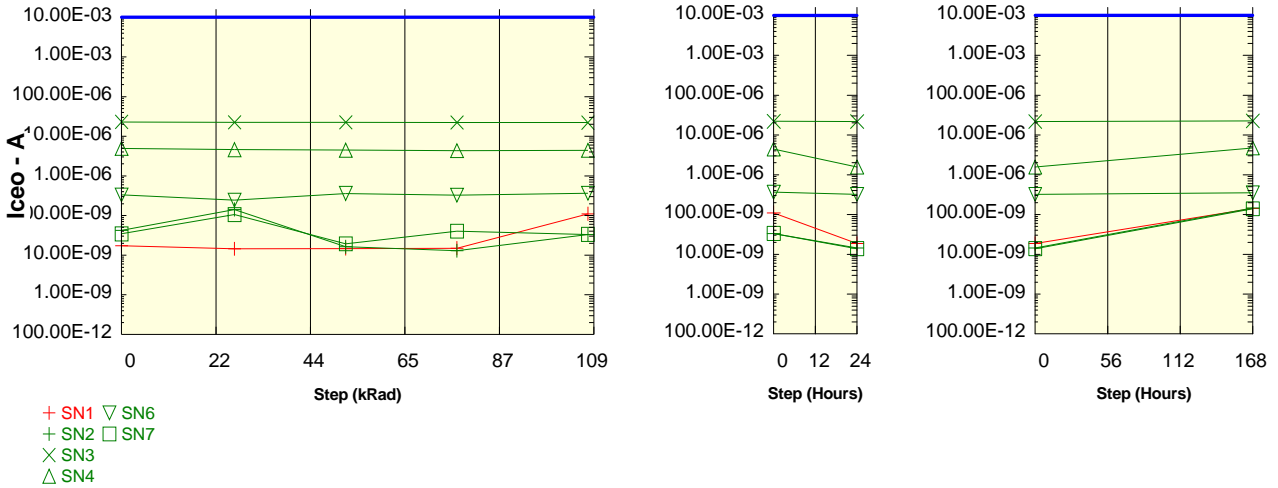
Measurements

Vceo	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	179.0	177.5	177.5	177.5	178.0	177.5	178.0
On samples							
SN2	177.5	179.0	179.0	178.5	179.5	179.0	178.5
SN3	177.5	178.5	179.0	178.0	179.0	179.5	178.5
SN4	178.5	179.0	179.5	179.5	180.0	179.5	179.0
SN6	178.0	178.5	178.5	178.5	179.0	179.0	178.0
SN7	178.0	178.5	179.5	179.5	179.5	179.0	178.5
Statistics							
Min	177.5	178.5	178.5	178.0	179.0	179.0	178.0
Max	178.5	179.0	179.5	179.5	180.0	179.5	179.0
Average	177.9	178.7	179.1	178.8	179.4	179.2	178.5
Sigma	0.4	0.2	0.4	0.6	0.4	0.2	0.3
(Vce) Lot WorstCase	176.8	178.0	178.0	177.0	178.3	178.5	177.6

Drift Calculation

Vceo	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	1.50E+00	1.50E+00	1.00E+00	2.00E+00	1.50E+00	1.00E+00
SN3	-	1.00E+00	1.50E+00	500.00E-03	1.50E+00	2.00E+00	1.00E+00
SN4	-	500.00E-03	1.00E+00	1.00E+00	1.50E+00	1.00E+00	500.00E-03
SN6	-	500.00E-03	500.00E-03	500.00E-03	1.00E+00	1.00E+00	0.00E+00
SN7	-	500.00E-03	1.50E+00	1.50E+00	1.50E+00	1.00E+00	500.00E-03
Average	-	800.00E-03	1.20E+00	900.00E-03	1.50E+00	1.30E+00	600.00E-03
Sigma	-	400.00E-03	400.00E-03	374.17E-03	316.23E-03	400.00E-03	374.17E-03
d(Vce) Lot WorstCase	-	-400.00E-03	-277.56E-18	-222.50E-03	551.32E-03	100.00E-03	-522.50E-03

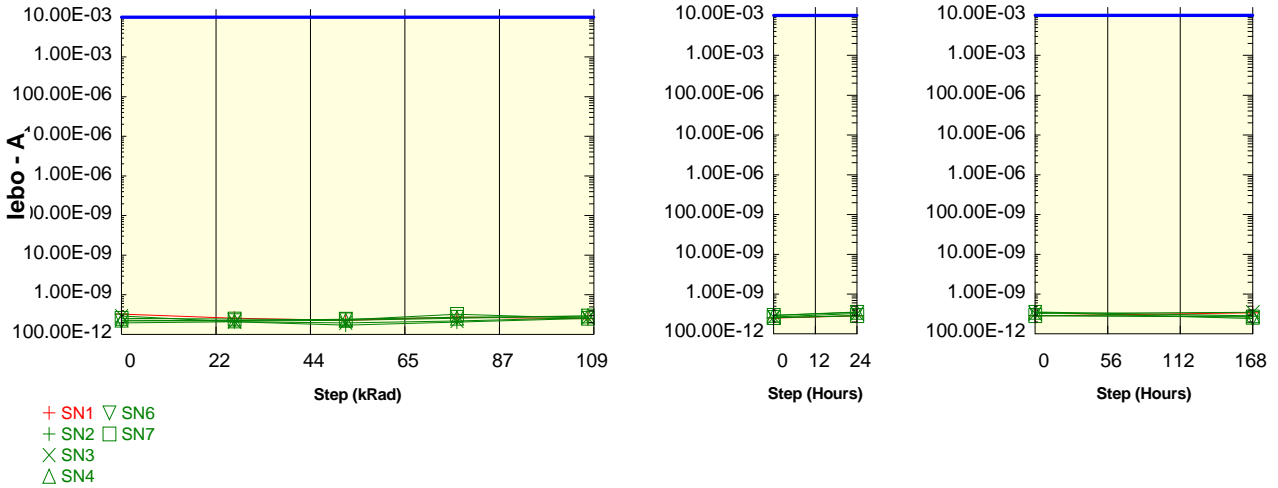
Test conditions : TID
Parameter : Collector to emitter cut-off current : I_{ceo}
V_{ce} = 80V
 Unit : A
 Spec Limit Max : 10.00E-03
 Spec limits are represented in bold lines on the graphic.



Measurements							
I _{ceo}	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	17.38E-09	14.53E-09	14.65E-09	15.04E-09	110.64E-09	18.61E-09	141.68E-09
On samples							
SN2	41.99E-09	143.26E-09	16.37E-09	12.92E-09	33.09E-09	14.42E-09	146.66E-09
SN3	23.01E-06	22.55E-06	22.41E-06	22.10E-06	22.00E-06	21.85E-06	22.46E-06
SN4	4.93E-06	4.59E-06	4.46E-06	4.32E-06	4.39E-06	1.57E-06	4.69E-06
SN6	331.36E-09	245.56E-09	361.62E-09	325.74E-09	365.88E-09	321.46E-09	354.64E-09
SN7	34.63E-09	106.02E-09	19.35E-09	40.35E-09	33.42E-09	13.86E-09	139.56E-09
Statistics							
Min	34.63E-09	106.02E-09	16.37E-09	12.92E-09	33.09E-09	13.86E-09	139.56E-09
Max	23.01E-06	22.55E-06	22.41E-06	22.10E-06	22.00E-06	21.85E-06	22.46E-06
Average	5.67E-06	5.53E-06	5.45E-06	5.36E-06	5.37E-06	4.75E-06	5.56E-06
Sigma	8.87E-06	8.68E-06	8.64E-06	8.53E-06	8.48E-06	8.57E-06	8.63E-06
(Ice) Lot WorstCase	32.28E-06	31.57E-06	31.38E-06	30.94E-06	30.81E-06	30.46E-06	31.44E-06

Drift Calculation							
I _{ceo}	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	101.27E-09	-25.62E-09	-29.07E-09	-8.90E-09	-27.57E-09	104.67E-09
SN3	-	-464.00E-09	-606.00E-09	-914.00E-09	-1.01E-06	-1.16E-06	-556.00E-09
SN4	-	-335.60E-09	-470.60E-09	-603.80E-09	-531.60E-09	-3.35E-06	-236.20E-09
SN6	-	-85.80E-09	30.26E-09	-5.62E-09	34.52E-09	-9.90E-09	23.28E-09
SN7	-	71.39E-09	-15.27E-09	5.72E-09	-1.21E-09	-20.76E-09	104.93E-09
Average	-	-142.55E-09	-217.45E-09	-309.35E-09	-303.84E-09	-915.13E-09	-111.86E-09
Sigma	-	223.18E-09	266.12E-09	380.10E-09	411.44E-09	1.30E-06	254.90E-09
d(Ice) Lot WorstCase	-	526.98E-09	580.90E-09	830.95E-09	930.49E-09	2.98E-06	652.83E-09

Test conditions : TID
Parameter : Emitter to base cut-off current : lebo
Veb = 7V
 Unit : A
 Spec Limit Max : 10.00E-03
 Spec limits are represented in bold lines on the graphic.



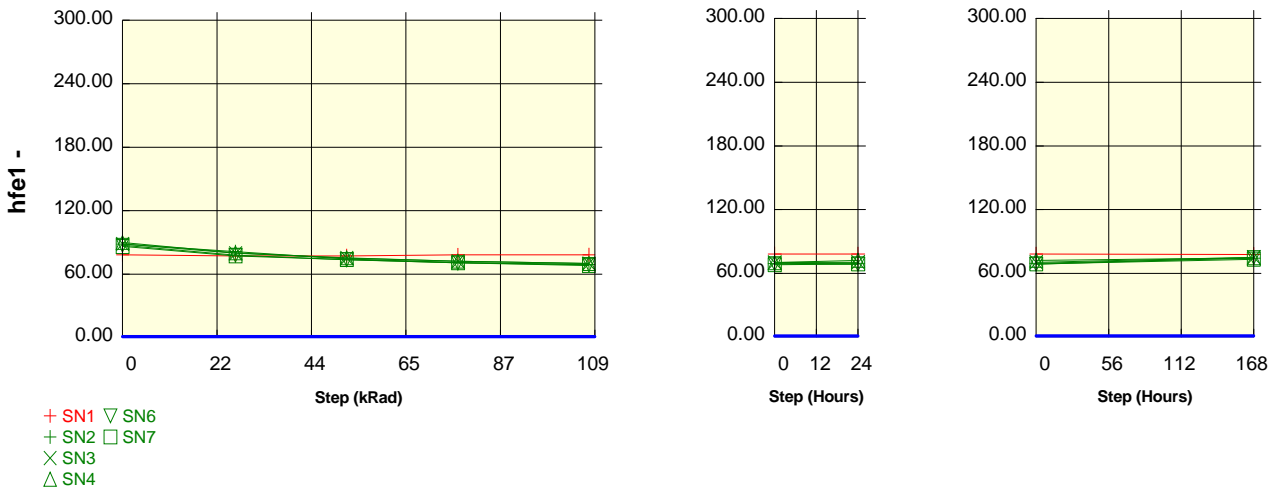
Measurements

lebo	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	326.96E-12	257.30E-12	226.00E-12	276.26E-12	249.60E-12	284.00E-12	336.80E-12
On samples							
SN2	195.88E-12	210.08E-12	173.18E-12	207.36E-12	254.80E-12	287.00E-12	278.20E-12
SN3	293.80E-12	209.14E-12	197.36E-12	221.10E-12	265.20E-12	326.00E-12	351.00E-12
SN4	230.30E-12	220.58E-12	228.14E-12	260.18E-12	295.80E-12	353.90E-12	286.60E-12
SN6	218.62E-12	223.94E-12	241.02E-12	269.68E-12	291.80E-12	350.20E-12	244.20E-12
SN7	254.54E-12	246.88E-12	235.28E-12	320.68E-12	259.20E-12	291.00E-12	265.40E-12
Statistics							
Min	195.88E-12	209.14E-12	173.18E-12	207.36E-12	254.80E-12	287.00E-12	244.20E-12
Max	293.80E-12	246.88E-12	241.02E-12	320.68E-12	295.80E-12	353.90E-12	351.00E-12
Average	238.63E-12	222.12E-12	215.00E-12	255.80E-12	273.36E-12	321.62E-12	285.08E-12
Sigma	33.45E-12	13.65E-12	25.77E-12	39.93E-12	17.06E-12	28.33E-12	35.93E-12
(lebo) Lot WorstCase	338.98E-12	263.09E-12	292.31E-12	375.59E-12	324.54E-12	406.62E-12	392.86E-12

Drift Calculation

lebo	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	14.20E-12	-22.70E-12	11.48E-12	58.92E-12	91.12E-12	82.32E-12
SN3	-	-84.66E-12	-96.44E-12	-72.70E-12	-28.60E-12	32.20E-12	57.20E-12
SN4	-	-9.72E-12	-2.16E-12	29.88E-12	65.50E-12	123.60E-12	56.30E-12
SN6	-	5.32E-12	22.40E-12	51.06E-12	73.18E-12	131.58E-12	25.58E-12
SN7	-	-7.66E-12	-19.26E-12	66.14E-12	4.66E-12	36.46E-12	10.86E-12
Average	-	-16.50E-12	-23.63E-12	17.17E-12	34.73E-12	82.99E-12	46.45E-12
Sigma	-	35.18E-12	39.75E-12	48.62E-12	39.81E-12	42.00E-12	25.30E-12
d(lebo) Lot WorstCase	-	89.04E-12	95.62E-12	163.02E-12	154.17E-12	209.00E-12	122.36E-12

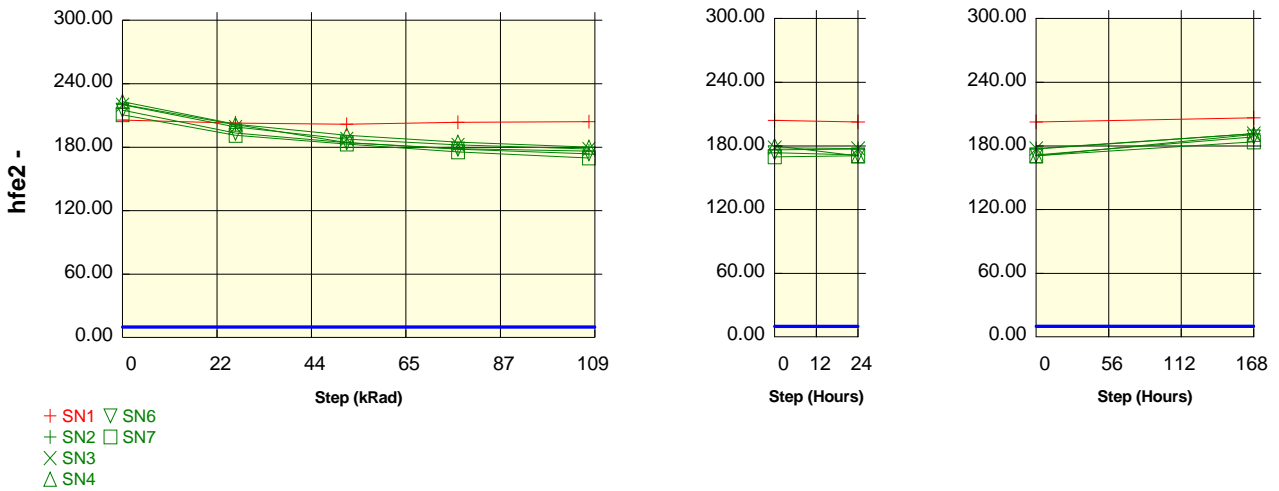
Test conditions : TID
Parameter : Forward-Current Transfer Ratio 1 : hfe1
Vce = 2V Ic = 100µA
 Unit :
 Spec Limit Min : 1.00
 Spec limits are represented in bold lines on the graphic.



Measurements							
hfe1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	78.26	77.22	77.20	78.09	78.25	78.03	77.74
On samples							
SN2	88.37	81.29	74.34	70.97	69.15	69.29	74.35
SN3	88.53	79.60	75.11	72.10	70.13	70.33	75.00
SN4	89.89	79.99	75.36	72.12	69.99	72.28	74.47
SN6	87.34	77.94	73.56	70.50	68.89	68.61	74.80
SN7	86.14	77.24	73.75	70.67	68.04	68.83	73.32
Statistics							
Min	86.14	77.24	73.56	70.50	68.04	68.61	73.32
Max	89.89	81.29	75.36	72.12	70.13	72.28	75.00
Average	88.05	79.21	74.43	71.27	69.24	69.87	74.39
Sigma	1.26	1.45	0.72	0.70	0.76	1.34	0.58
(hfe) Lot WorstCase	84.29	74.86	72.28	69.17	66.95	65.84	72.64

Drift Calculation							
hfe1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	985.35E-06	2.13E-03	2.77E-03	3.14E-03	3.12E-03	2.13E-03
SN3	-	1.27E-03	2.02E-03	2.57E-03	2.96E-03	2.92E-03	2.04E-03
SN4	-	1.38E-03	2.14E-03	2.74E-03	3.16E-03	2.71E-03	2.30E-03
SN6	-	1.38E-03	2.14E-03	2.73E-03	3.07E-03	3.12E-03	1.92E-03
SN7	-	1.34E-03	1.95E-03	2.54E-03	3.09E-03	2.92E-03	2.03E-03
Average	-	1.27E-03	2.08E-03	2.67E-03	3.09E-03	2.96E-03	2.08E-03
Sigma	-	147.75E-06	79.79E-06	95.64E-06	70.43E-06	152.48E-06	129.14E-06
d(1/hfe) Lot WorstCase	-	1.71E-03	2.32E-03	2.96E-03	3.30E-03	3.42E-03	2.47E-03

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 2 : hfe2
Vce = 2V Ic = 1mA
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



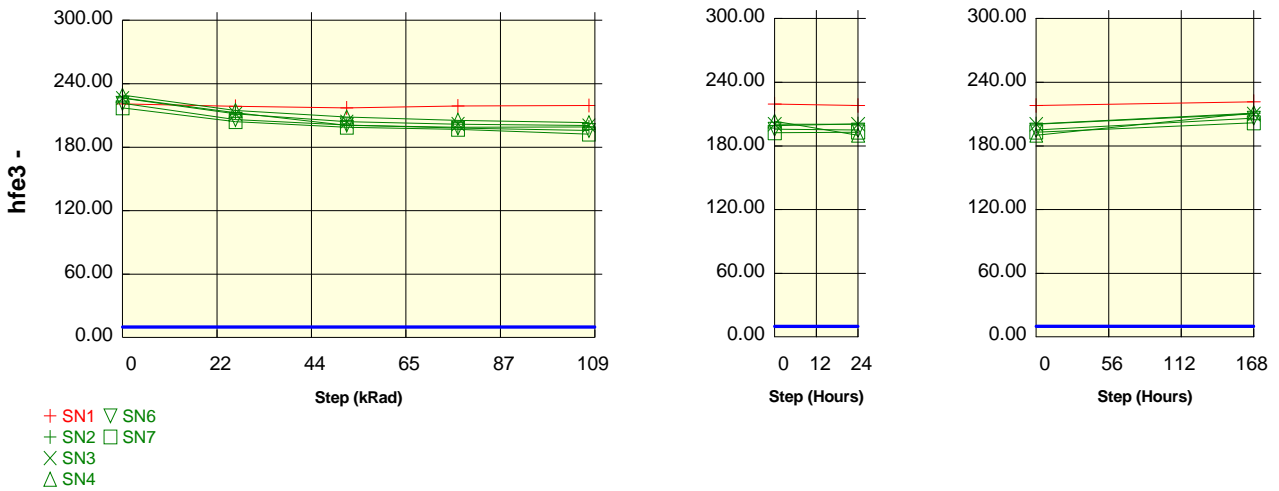
Measurements

hfe2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	205.71	202.90	201.80	203.62	204.15	202.64	206.35
On samples							
SN2	220.36	201.59	184.20	178.53	176.35	177.14	191.46
SN3	220.13	199.05	187.78	182.24	178.33	177.58	191.48
SN4	223.16	201.74	191.41	184.85	180.02	170.48	190.91
SN6	214.94	193.33	184.28	178.14	173.60	171.48	188.48
SN7	210.51	191.24	183.02	175.56	169.87	170.79	183.91
Statistics							
Min	210.51	191.24	183.02	175.56	169.87	170.48	183.91
Max	223.16	201.74	191.41	184.85	180.02	177.58	191.48
Average	217.82	197.39	186.14	179.86	175.64	173.50	189.25
Sigma	4.52	4.33	3.08	3.28	3.59	3.18	2.89
(hfe) Lot WorstCase	204.27	184.41	176.90	170.02	164.87	163.97	180.58

Drift Calculation

hfe2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	422.51E-06	891.01E-06	1.06E-03	1.13E-03	1.11E-03	684.97E-06
SN3	-	481.20E-06	782.81E-06	944.49E-06	1.06E-03	1.09E-03	679.92E-06
SN4	-	475.80E-06	743.22E-06	928.76E-06	1.07E-03	1.38E-03	756.92E-06
SN6	-	519.92E-06	773.99E-06	960.98E-06	1.11E-03	1.18E-03	653.05E-06
SN7	-	478.74E-06	713.55E-06	945.93E-06	1.14E-03	1.10E-03	687.17E-06
Average	-	475.63E-06	780.92E-06	968.69E-06	1.10E-03	1.17E-03	692.41E-06
Sigma	-	31.06E-06	60.22E-06	48.39E-06	29.42E-06	110.40E-06	34.49E-06
d(1/hfe) Lot WorstCase	-	568.82E-06	961.57E-06	1.11E-03	1.19E-03	1.50E-03	795.89E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 3 : hfe3
Vce = 2V Ic = 10mA
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



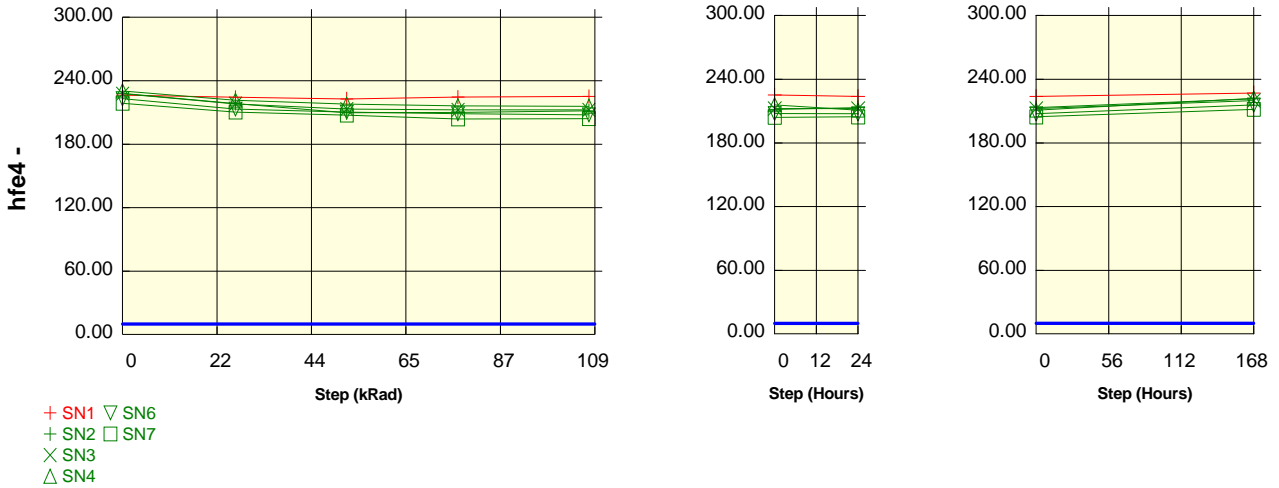
Measurements

hfe3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	220.96	218.66	217.09	218.91	219.46	218.19	221.61
On samples							
SN2	226.60	212.69	200.74	198.89	199.17	200.66	210.97
SN3	226.39	211.55	204.15	201.82	200.44	200.46	209.99
SN4	229.23	214.69	208.51	205.46	203.31	190.09	211.10
SN6	221.44	206.27	201.05	198.04	195.75	194.90	206.15
SN7	217.15	204.17	198.93	196.77	192.46	192.97	201.84
Statistics							
Min	217.15	204.17	198.93	196.77	192.46	190.09	201.84
Max	229.23	214.69	208.51	205.46	203.31	200.66	211.10
Average	224.16	209.87	202.67	200.20	198.23	195.82	208.01
Sigma	4.32	3.98	3.37	3.11	3.77	4.17	3.57
(hfe) Lot WorstCase	211.21	197.92	192.58	190.86	186.91	183.32	197.29

Drift Calculation

hfe3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	288.71E-06	568.53E-06	614.92E-06	607.65E-06	570.54E-06	326.93E-06
SN3	-	309.79E-06	481.21E-06	537.76E-06	571.84E-06	571.24E-06	345.04E-06
SN4	-	295.48E-06	433.57E-06	504.68E-06	556.05E-06	898.25E-06	374.64E-06
SN6	-	332.01E-06	457.99E-06	533.58E-06	592.74E-06	614.82E-06	334.81E-06
SN7	-	292.67E-06	421.84E-06	476.90E-06	590.82E-06	577.09E-06	349.40E-06
Average	-	303.73E-06	472.63E-06	533.57E-06	583.82E-06	646.39E-06	346.17E-06
Sigma	-	15.83E-06	52.13E-06	46.22E-06	17.95E-06	126.99E-06	16.26E-06
d(1/hfe) Lot WorstCase	-	351.21E-06	629.03E-06	672.23E-06	637.67E-06	1.03E-03	394.93E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 4 : hfe4
Vce = 2V Ic = 100mA
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



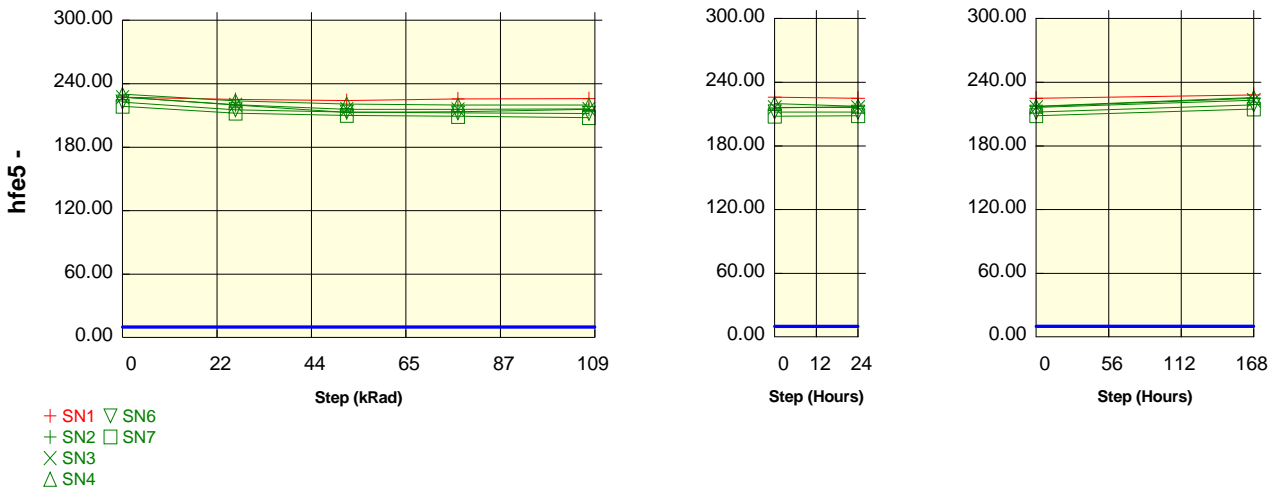
Measurements

hfe4	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	226.52	224.31	222.92	224.52	225.04	223.80	227.06
On samples							
SN2	227.96	218.35	209.92	209.96	211.55	213.07	221.52
SN3	227.81	218.23	213.17	212.36	212.38	212.37	219.93
SN4	230.44	221.60	217.82	216.43	215.90	210.91	222.13
SN6	222.97	213.24	210.37	208.82	207.79	207.35	215.66
SN7	218.74	210.38	207.53	203.85	204.19	204.52	211.58
Statistics							
Min	218.74	210.38	207.53	203.85	204.19	204.52	211.58
Max	230.44	221.60	217.82	216.43	215.90	213.07	222.13
Average	225.59	216.36	211.77	210.28	210.36	209.64	218.16
Sigma	4.19	4.01	3.52	4.14	4.02	3.23	3.99
(hfe) Lot WorstCase	213.01	204.33	201.21	197.86	198.29	199.95	206.18

Drift Calculation

hfe4	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	193.07E-06	376.97E-06	376.09E-06	340.40E-06	306.62E-06	127.68E-06
SN3	-	192.85E-06	301.43E-06	319.34E-06	318.91E-06	319.16E-06	157.37E-06
SN4	-	173.04E-06	251.32E-06	280.96E-06	292.15E-06	401.94E-06	162.28E-06
SN6	-	204.58E-06	268.58E-06	303.99E-06	327.65E-06	337.78E-06	151.96E-06
SN7	-	181.64E-06	246.94E-06	334.10E-06	325.88E-06	317.89E-06	154.85E-06
Average	-	189.03E-06	289.05E-06	322.90E-06	321.00E-06	336.68E-06	150.83E-06
Sigma	-	10.80E-06	47.96E-06	31.89E-06	16.01E-06	34.13E-06	12.06E-06
d(1/hfe) Lot WorstCase	-	221.43E-06	432.91E-06	418.55E-06	369.02E-06	439.06E-06	187.01E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 5 : hfe5
Vce = 2V Ic = 500mA
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



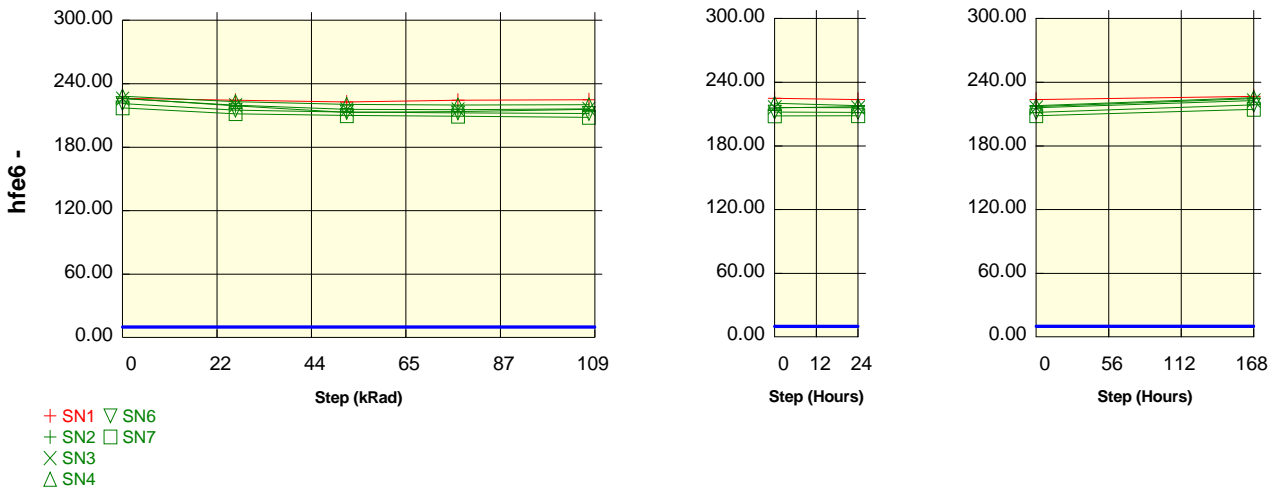
Measurements

hfe5	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	227.33	225.21	223.98	225.55	225.97	224.95	228.11
On samples							
SN2	227.45	220.03	212.82	213.56	215.72	217.16	224.93
SN3	227.27	220.10	215.89	215.69	216.28	216.25	223.01
SN4	230.13	223.89	220.86	219.93	219.99	217.48	225.61
SN6	222.68	215.38	213.23	212.36	211.97	211.80	218.68
SN7	218.59	212.22	210.12	209.18	208.09	208.48	214.78
Statistics							
Min	218.59	212.22	210.12	209.18	208.09	208.48	214.78
Max	230.13	223.89	220.86	219.93	219.99	217.48	225.61
Average	225.22	218.32	214.58	214.14	214.41	214.23	221.40
Sigma	4.09	4.07	3.63	3.58	4.05	3.53	4.10
(hfe) Lot WorstCase	212.95	206.11	203.69	203.40	202.25	203.65	209.10

Drift Calculation

hfe5	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	148.25E-06	302.08E-06	285.82E-06	238.96E-06	208.21E-06	49.07E-06
SN3	-	143.43E-06	231.99E-06	236.22E-06	223.58E-06	224.42E-06	84.23E-06
SN4	-	121.04E-06	182.47E-06	201.59E-06	200.33E-06	252.75E-06	87.08E-06
SN6	-	152.09E-06	199.04E-06	218.25E-06	226.82E-06	230.68E-06	81.99E-06
SN7	-	137.30E-06	184.46E-06	205.97E-06	230.83E-06	221.89E-06	81.29E-06
Average	-	140.42E-06	220.01E-06	229.57E-06	224.10E-06	227.59E-06	76.73E-06
Sigma	-	10.88E-06	44.70E-06	30.58E-06	12.95E-06	14.56E-06	13.98E-06
d(1/hfe) Lot WorstCase	-	173.06E-06	354.12E-06	321.32E-06	262.97E-06	271.28E-06	118.67E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 6 : hfe6
Vce = 2V Ic = 1A
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



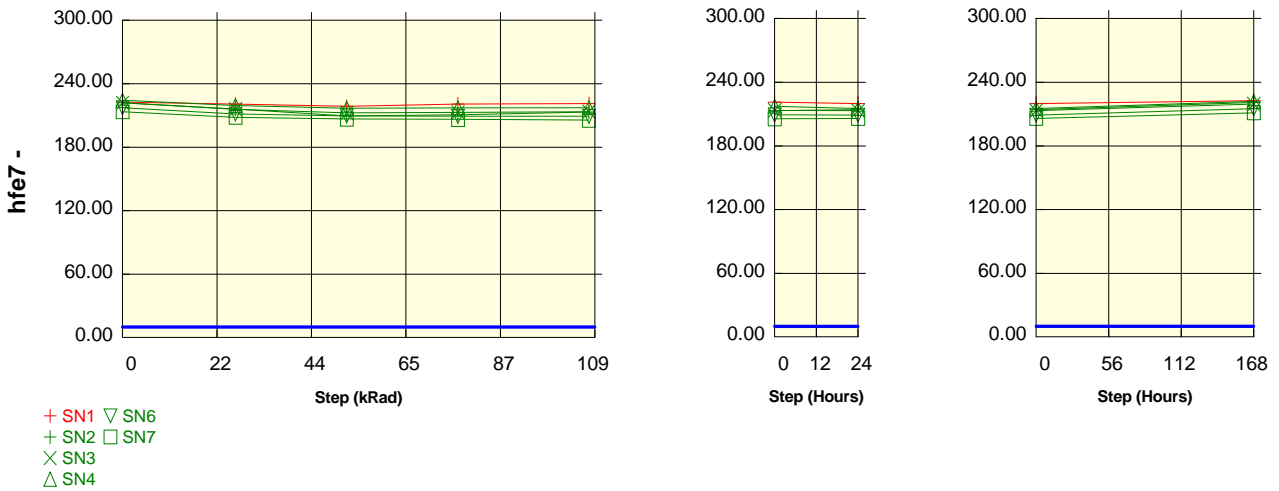
Measurements

hfe6	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	226.31	224.27	222.77	224.38	224.89	223.65	226.80
On samples							
SN2	226.12	219.25	212.81	213.70	215.80	217.06	224.61
SN3	225.93	219.58	215.71	215.65	216.33	216.09	222.85
SN4	228.40	223.09	220.45	219.92	220.12	217.84	225.53
SN6	221.21	214.96	213.11	212.35	211.89	211.66	218.53
SN7	217.16	211.74	209.95	209.40	208.20	208.45	214.56
Statistics							
Min	217.16	211.74	209.95	209.40	208.20	208.45	214.56
Max	228.40	223.09	220.45	219.92	220.12	217.84	225.53
Average	223.76	217.73	214.41	214.21	214.47	214.22	221.21
Sigma	4.05	3.95	3.53	3.51	4.08	3.59	4.11
(hfe) Lot WorstCase	211.63	205.87	203.81	203.68	202.23	203.45	208.90

Drift Calculation

hfe6	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	138.55E-06	276.68E-06	257.00E-06	211.62E-06	184.54E-06	29.75E-06
SN3	-	127.81E-06	209.59E-06	210.96E-06	196.28E-06	201.43E-06	61.14E-06
SN4	-	104.11E-06	157.78E-06	168.72E-06	164.58E-06	212.23E-06	55.67E-06
SN6	-	131.46E-06	171.77E-06	188.53E-06	198.84E-06	203.88E-06	55.47E-06
SN7	-	117.86E-06	158.17E-06	170.56E-06	198.27E-06	192.34E-06	55.77E-06
Average	-	123.96E-06	194.80E-06	199.15E-06	193.92E-06	198.88E-06	51.56E-06
Sigma	-	11.96E-06	45.09E-06	32.69E-06	15.64E-06	9.57E-06	11.11E-06
d(1/hfe) Lot WorstCase	-	159.84E-06	330.07E-06	297.22E-06	240.83E-06	227.60E-06	84.90E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 7 : hfe7
Vce = 2V Ic = 2A
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



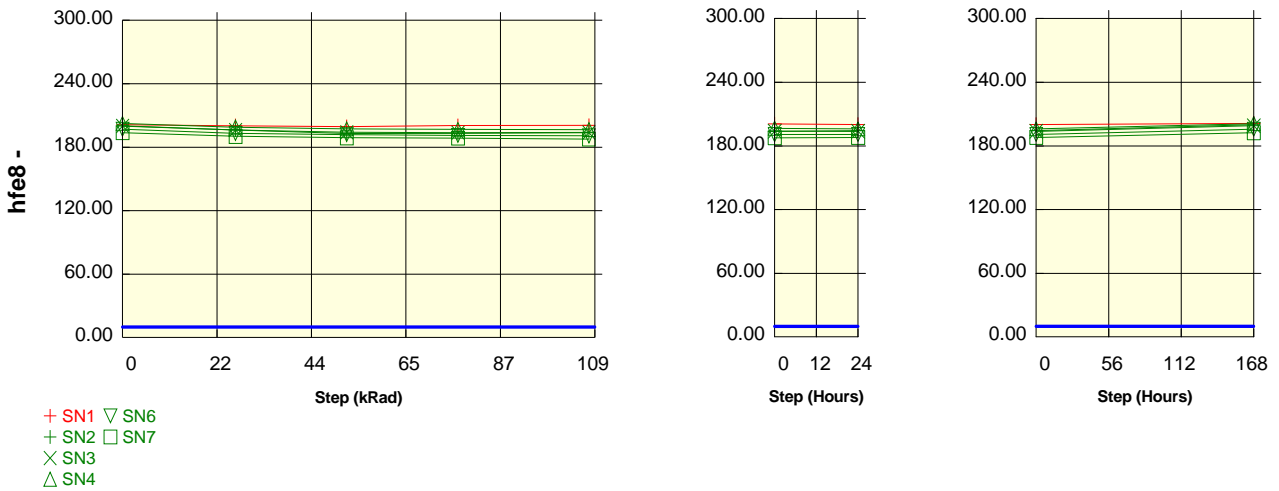
Measurements

hfe7	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	222.56	220.70	218.60	220.71	221.18	220.00	222.51
On samples							
SN2	222.11	215.99	209.57	210.59	213.10	214.23	220.97
SN3	221.92	215.89	212.31	212.91	213.52	213.20	219.30
SN4	224.28	219.37	216.85	217.09	217.29	215.28	221.96
SN6	217.33	211.30	209.65	209.16	209.17	209.08	215.03
SN7	213.38	208.22	206.56	206.34	205.56	206.03	211.21
Statistics							
Min	213.38	208.22	206.56	206.34	205.56	206.03	211.21
Max	224.28	219.37	216.85	217.09	217.29	215.28	221.96
Average	219.80	214.15	210.99	211.22	211.73	211.56	217.69
Sigma	3.93	3.92	3.45	3.63	4.02	3.48	4.01
(hfe) Lot WorstCase	208.01	202.38	200.64	200.33	199.68	201.13	205.65

Drift Calculation

hfe7	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	127.51E-06	269.44E-06	246.20E-06	190.30E-06	165.51E-06	23.19E-06
SN3	-	125.90E-06	203.82E-06	190.61E-06	177.21E-06	184.29E-06	53.70E-06
SN4	-	99.75E-06	152.88E-06	147.75E-06	143.53E-06	186.38E-06	46.71E-06
SN6	-	131.23E-06	168.52E-06	179.70E-06	179.38E-06	181.50E-06	49.16E-06
SN7	-	116.11E-06	154.68E-06	159.97E-06	178.39E-06	167.30E-06	48.10E-06
Average	-	120.10E-06	189.87E-06	184.85E-06	173.76E-06	177.00E-06	44.17E-06
Sigma	-	11.34E-06	43.79E-06	34.11E-06	15.83E-06	8.80E-06	10.75E-06
d(1/hfe) Lot WorstCase	-	154.11E-06	321.24E-06	287.19E-06	221.24E-06	203.40E-06	76.43E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 8 : hfe8
Vce = 2V Ic = 4A
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



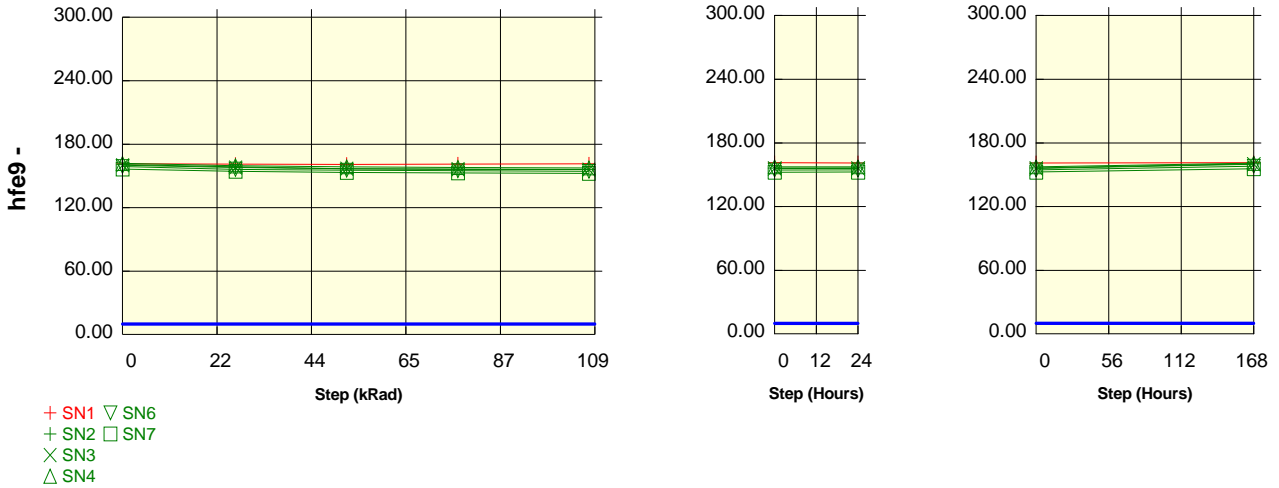
Measurements

hfe8	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	201.13	200.27	199.50	200.37	200.60	200.06	201.35
On samples							
SN2	200.29	196.33	192.89	193.03	193.78	194.42	199.89
SN3	200.01	196.25	194.09	193.71	193.84	193.80	199.01
SN4	202.52	199.00	197.32	196.81	196.66	196.03	201.04
SN6	196.98	193.04	191.78	191.14	190.73	190.85	195.79
SN7	193.63	190.20	188.91	188.47	187.66	187.95	192.46
Statistics							
Min	193.63	190.20	188.91	188.47	187.66	187.95	192.46
Max	202.52	199.00	197.32	196.81	196.66	196.03	201.04
Average	198.69	194.96	193.00	192.63	192.53	192.61	197.64
Sigma	3.08	3.04	2.76	2.77	3.07	2.87	3.12
(hfe) Lot WorstCase	189.44	185.84	184.73	184.32	183.31	184.00	188.27

Drift Calculation

hfe8	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	100.64E-06	191.55E-06	187.82E-06	167.80E-06	150.76E-06	9.97E-06
SN3	-	95.83E-06	152.62E-06	162.53E-06	159.21E-06	160.11E-06	25.02E-06
SN4	-	87.33E-06	130.16E-06	143.19E-06	147.24E-06	163.39E-06	36.33E-06
SN6	-	103.73E-06	137.53E-06	155.20E-06	166.34E-06	163.17E-06	30.95E-06
SN7	-	93.31E-06	129.03E-06	141.43E-06	164.36E-06	156.05E-06	31.54E-06
Average	-	96.17E-06	148.18E-06	158.03E-06	160.99E-06	158.70E-06	26.76E-06
Sigma	-	5.72E-06	23.26E-06	16.80E-06	7.47E-06	4.78E-06	9.13E-06
d(1/hfe) Lot WorstCase	-	113.32E-06	217.97E-06	208.44E-06	183.39E-06	173.02E-06	54.16E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 9 : hfe9
Vce = 2V Ic = 6A
 Unit :
 Spec Limit Min : 10.00
 Spec limits are represented in bold lines on the graphic.



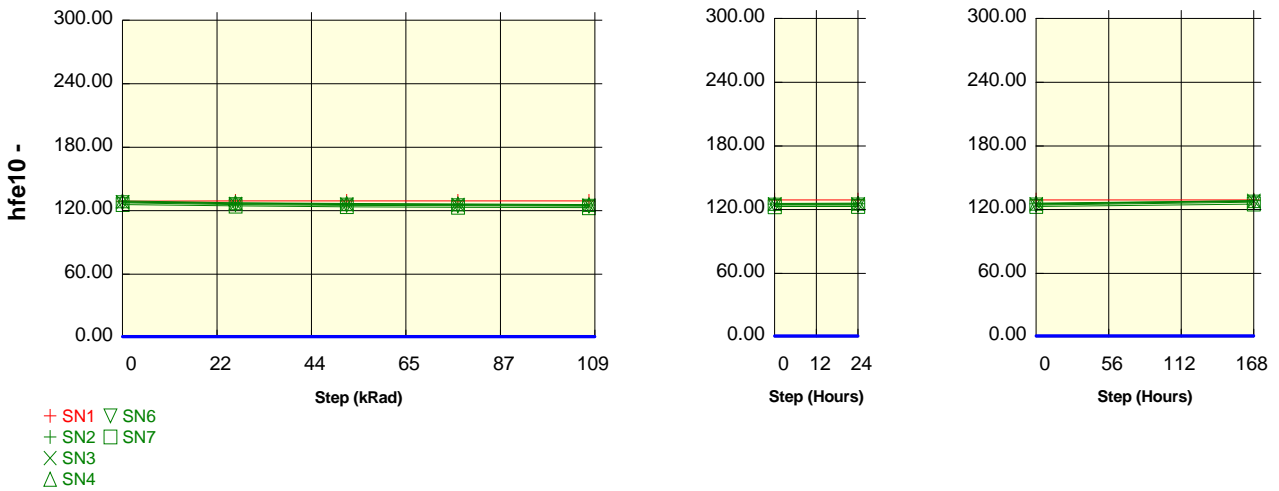
Measurements

hfe9	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	161.33	161.20	161.02	161.26	161.32	161.19	161.40
On samples							
SN2	160.56	158.43	156.83	156.40	156.21	156.47	160.26
SN3	160.12	157.93	156.81	156.32	155.93	156.01	159.82
SN4	161.84	159.49	158.51	157.93	157.45	157.52	160.78
SN6	158.75	156.31	155.45	154.87	154.38	154.54	158.03
SN7	156.41	154.36	153.43	152.85	152.33	152.49	155.71
Statistics							
Min	156.41	154.36	153.43	152.85	152.33	152.49	155.71
Max	161.84	159.49	158.51	157.93	157.45	157.52	160.78
Average	159.54	157.30	156.21	155.67	155.26	155.41	158.92
Sigma	1.85	1.80	1.69	1.71	1.76	1.74	1.85
(hfe) Lot WorstCase	154.00	151.91	151.12	150.54	149.98	150.17	153.36

Drift Calculation

hfe9	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	83.66E-06	147.94E-06	165.65E-06	173.53E-06	162.85E-06	11.39E-06
SN3	-	86.65E-06	131.86E-06	151.79E-06	167.69E-06	164.56E-06	11.68E-06
SN4	-	90.77E-06	129.56E-06	152.83E-06	172.16E-06	169.32E-06	40.42E-06
SN6	-	98.60E-06	133.68E-06	157.83E-06	178.37E-06	171.49E-06	28.64E-06
SN7	-	85.11E-06	124.34E-06	148.90E-06	171.29E-06	164.44E-06	28.90E-06
Average	-	88.96E-06	133.48E-06	155.40E-06	172.61E-06	166.53E-06	24.21E-06
Sigma	-	5.37E-06	7.88E-06	5.88E-06	3.47E-06	3.29E-06	11.19E-06
d(1/hfe) Lot WorstCase	-	105.07E-06	157.11E-06	173.04E-06	183.01E-06	176.40E-06	57.77E-06

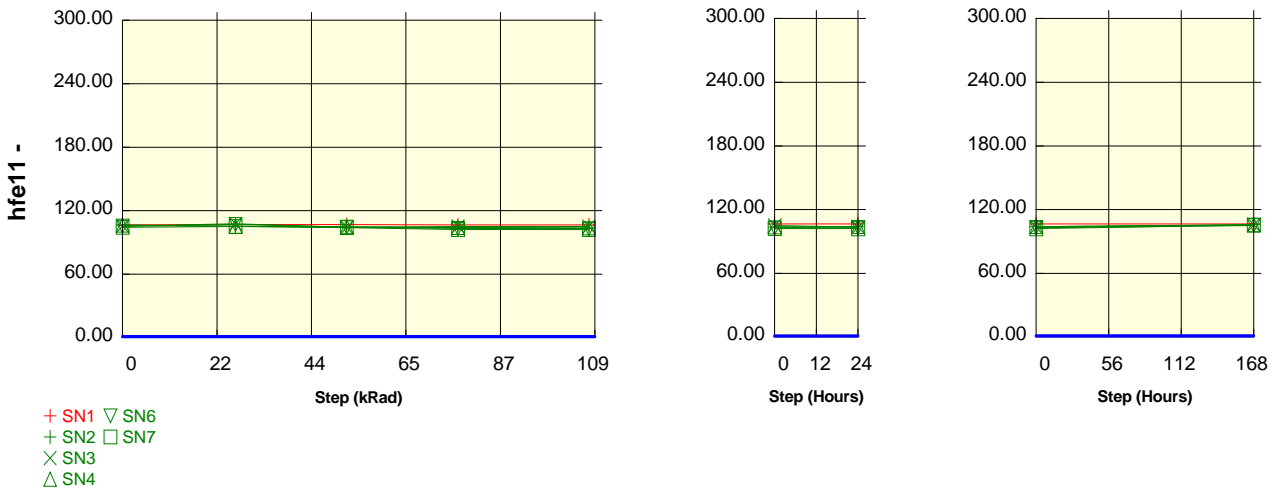
Test conditions : TID
Parameter : Forward-Current Transfer Ratio 10 : hfe10
Vce = 2V Ic = 8A
 Unit :
 Spec Limit Min : 1.00
 Spec limits are represented in bold lines on the graphic.



Measurements							
hfe10	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	129.01	129.09	129.05	129.12	129.12	129.11	129.09
On samples							
SN2	128.45	127.11	126.21	125.69	125.30	125.47	128.30
SN3	127.99	126.56	125.87	125.37	125.02	125.05	127.95
SN4	129.10	127.44	126.76	126.26	125.75	126.00	128.35
SN6	127.41	125.75	125.11	124.60	124.16	124.33	126.96
SN7	125.80	124.40	123.73	123.21	122.78	122.91	125.34
Statistics							
Min	125.80	124.40	123.73	123.21	122.78	122.91	125.34
Max	129.10	127.44	126.76	126.26	125.75	126.00	128.35
Average	127.75	126.25	125.54	125.03	124.60	124.75	127.38
Sigma	1.12	1.09	1.05	1.05	1.05	1.07	1.14
(hfe) Lot WorstCase	124.39	122.98	122.39	121.86	121.46	121.54	123.97

Drift Calculation							
hfe10	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	81.73E-06	137.87E-06	170.61E-06	195.65E-06	184.47E-06	8.87E-06
SN3	-	88.14E-06	131.70E-06	163.40E-06	185.68E-06	183.38E-06	2.16E-06
SN4	-	100.59E-06	142.97E-06	174.26E-06	206.11E-06	190.41E-06	45.07E-06
SN6	-	103.86E-06	144.38E-06	176.96E-06	205.46E-06	194.37E-06	27.70E-06
SN7	-	89.98E-06	133.26E-06	167.47E-06	195.58E-06	187.37E-06	29.62E-06
Average	-	92.86E-06	138.04E-06	170.54E-06	197.70E-06	188.00E-06	22.69E-06
Sigma	-	8.19E-06	5.05E-06	4.81E-06	7.54E-06	4.02E-06	15.40E-06
d(1/hfe) Lot WorstCase	-	117.42E-06	153.19E-06	184.96E-06	220.31E-06	200.05E-06	68.89E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 11 : hfe11
Vce = 2V Ic = 10A
 Unit :
 Spec Limit Min : 1.00
 Spec limits are represented in bold lines on the graphic.



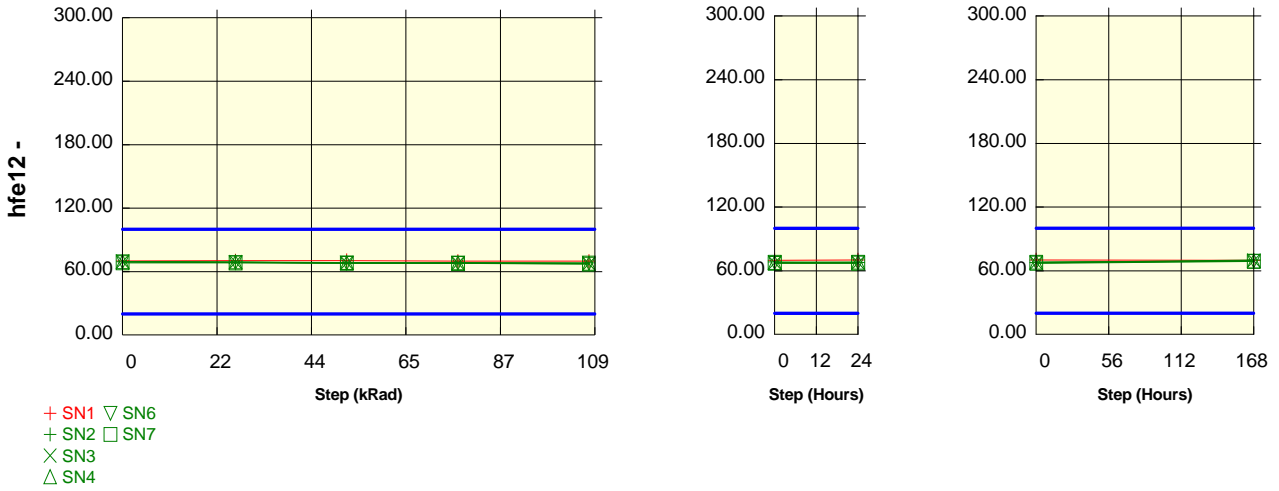
Measurements

hfe11	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	106.40	106.67	106.77	106.54	106.57	106.55	106.46
On samples							
SN2	106.00	105.20	104.57	103.80	103.53	103.80	105.78
SN3	105.53	107.55	104.22	105.04	105.02	103.38	105.64
SN4	106.39	105.09	104.79	103.97	103.63	104.00	105.61
SN6	105.33	106.96	104.27	103.05	102.78	102.98	104.93
SN7	104.11	104.90	103.92	102.03	102.06	102.01	105.53
Statistics							
Min	104.11	104.90	103.92	102.03	102.06	102.01	104.93
Max	106.39	107.55	104.79	105.04	105.02	104.00	105.78
Average	105.47	105.94	104.36	103.58	103.40	103.24	105.50
Sigma	0.77	1.09	0.30	1.00	0.99	0.71	0.29
(hfe) Lot WorstCase	103.15	102.66	103.46	100.57	100.44	101.11	104.62

Drift Calculation

hfe11	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	72.22E-06	129.56E-06	200.13E-06	225.68E-06	199.75E-06	19.34E-06
SN3	-	-177.61E-06	119.11E-06	44.34E-06	46.59E-06	197.13E-06	-9.43E-06
SN4	-	116.03E-06	143.44E-06	219.25E-06	250.54E-06	216.04E-06	69.61E-06
SN6	-	-144.59E-06	95.89E-06	209.28E-06	235.30E-06	215.98E-06	35.45E-06
SN7	-	-71.67E-06	17.72E-06	196.13E-06	193.51E-06	198.19E-06	-129.01E-06
Average	-	-41.12E-06	101.14E-06	173.82E-06	190.32E-06	205.42E-06	-2.81E-06
Sigma	-	116.46E-06	44.51E-06	65.23E-06	74.26E-06	8.69E-06	68.07E-06
d(1/hfe) Lot WorstCase	-	308.25E-06	234.67E-06	369.53E-06	413.09E-06	231.48E-06	201.41E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 12 : hfe12
Vce = 2V Ic = 15A
 Unit :
 Spec Limit Min : 20.00
 Spec Limit Max : 100.00
 Spec limits are represented in bold lines on the graphic.



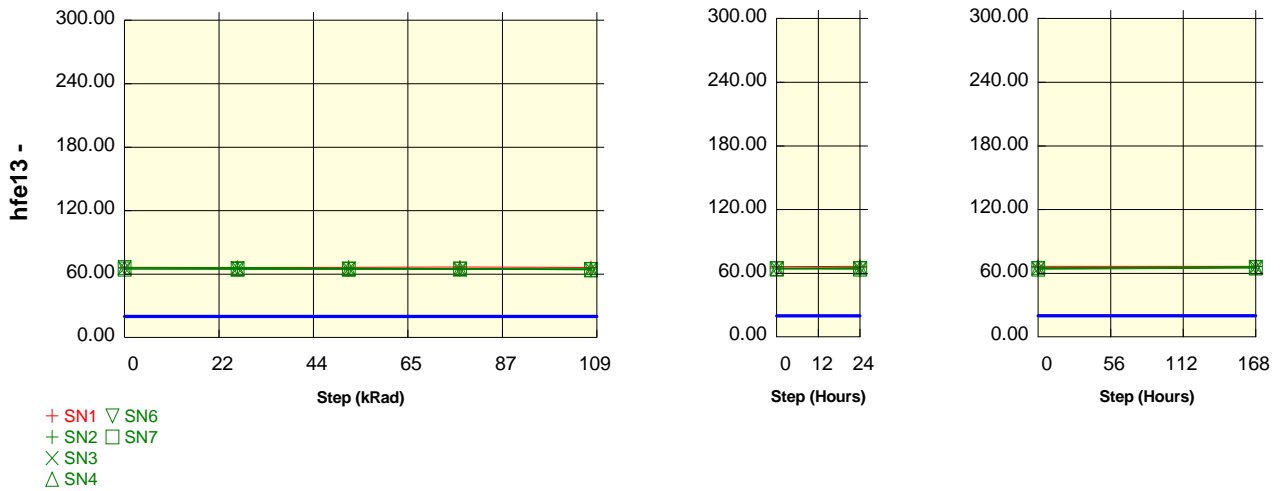
Measurements

hfe12	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	70.14	70.33	70.43	69.86	69.77	70.00	69.72
On samples							
SN2	69.44	68.90	68.12	68.49	68.18	67.84	70.00
SN3	69.44	68.90	68.22	67.87	67.57	67.53	69.54
SN4	69.44	69.03	68.58	68.27	67.75	68.18	69.17
SN6	69.22	68.49	68.14	67.96	67.87	67.87	69.12
SN7	68.36	68.18	67.78	67.66	66.96	67.05	68.81
Statistics							
Min	68.36	68.18	67.78	67.66	66.96	67.05	68.81
Max	69.44	69.03	68.58	68.49	68.18	68.18	70.00
Average	69.18	68.70	68.17	68.05	67.67	67.70	69.33
Sigma	0.42	0.32	0.26	0.30	0.40	0.38	0.41
(hfe) Lot WorstCase	67.93	67.75	67.40	67.16	66.45	66.55	68.10

Drift Calculation

hfe12	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	113.98E-06	279.43E-06	200.00E-06	266.67E-06	341.04E-06	-114.28E-06
SN3	-	113.98E-06	258.13E-06	333.33E-06	400.00E-06	407.44E-06	-19.18E-06
SN4	-	85.98E-06	180.56E-06	247.14E-06	360.64E-06	266.67E-06	57.83E-06
SN6	-	152.60E-06	227.23E-06	266.31E-06	285.93E-06	285.93E-06	19.26E-06
SN7	-	39.01E-06	125.34E-06	152.63E-06	305.67E-06	285.79E-06	-94.33E-06
Average	-	101.11E-06	214.14E-06	239.88E-06	323.78E-06	317.37E-06	-30.14E-06
Sigma	-	37.60E-06	55.46E-06	61.13E-06	49.38E-06	51.44E-06	65.57E-06
d(1/hfe) Lot WorstCase	-	213.90E-06	380.53E-06	423.29E-06	471.91E-06	471.68E-06	166.59E-06

Test conditions : TID
Parameter : Forward-Current Transfer Ratio 13 : hfe13
Vce = 5V Ic = 20A
 Unit :
 Spec Limit Min : 20.00
 Spec limits are represented in bold lines on the graphic.



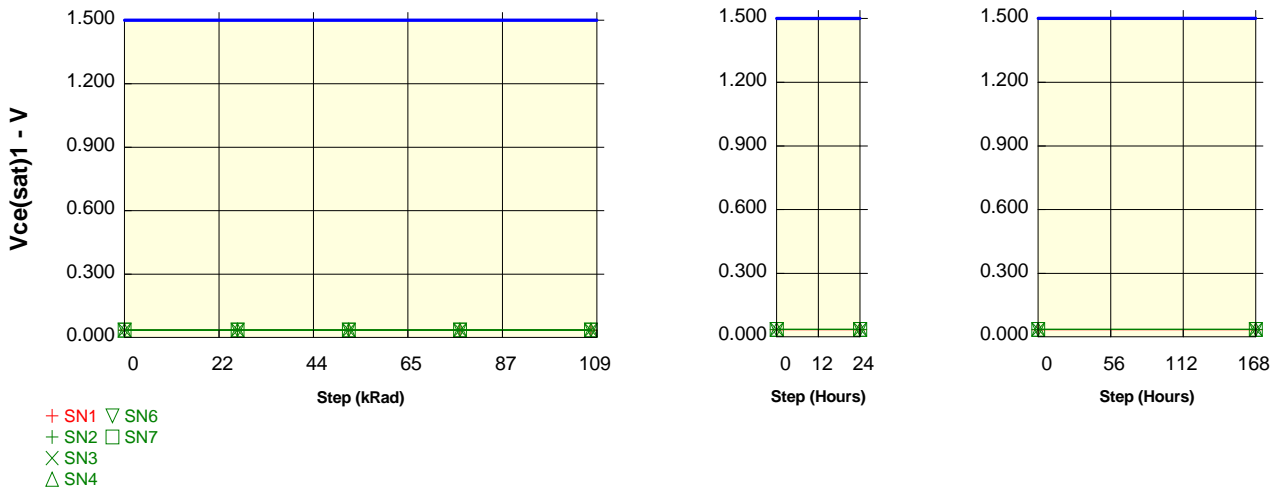
Measurements

hfe13	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	66.36	66.23	66.58	66.67	66.07	66.51	66.45
On samples							
SN2	65.62	66.07	65.79	65.06	64.94	65.15	66.23
SN3	65.72	65.64	65.06	64.71	64.79	64.44	65.79
SN4	65.94	65.23	65.15	65.15	64.42	65.15	65.72
SN6	66.09	65.21	64.92	64.71	64.23	64.66	65.64
SN7	64.71	64.44	64.44	64.58	64.03	63.97	65.02
Statistics							
Min	64.71	64.44	64.44	64.58	64.03	63.97	65.02
Max	66.09	66.07	65.79	65.15	64.94	65.15	66.23
Average	65.62	65.32	65.07	64.84	64.48	64.67	65.68
Sigma	0.48	0.54	0.44	0.22	0.34	0.45	0.39
(hfe) Lot WorstCase	64.17	63.69	63.77	64.18	63.46	63.34	64.51

Drift Calculation

hfe13	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	-104.18E-06	-39.04E-06	130.22E-06	160.96E-06	110.96E-06	-139.04E-06
SN3	-	19.55E-06	154.05E-06	238.42E-06	219.35E-06	303.75E-06	-15.21E-06
SN4	-	165.49E-06	184.83E-06	184.83E-06	357.22E-06	184.83E-06	50.05E-06
SN6	-	204.40E-06	273.53E-06	323.38E-06	438.60E-06	335.20E-06	104.50E-06
SN7	-	65.32E-06	65.32E-06	30.88E-06	165.12E-06	177.63E-06	-72.88E-06
Average	-	70.12E-06	127.74E-06	181.55E-06	268.25E-06	222.47E-06	-14.52E-06
Sigma	-	109.63E-06	106.69E-06	98.69E-06	110.88E-06	83.88E-06	86.31E-06
d(1/hfe) Lot WorstCase	-	399.00E-06	447.82E-06	477.61E-06	600.89E-06	474.11E-06	244.42E-06

Test conditions : TID
Parameter : Collector- Emitter Saturation Voltage : Vce(sat)1
Ic = 1A Ib = 100mA
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



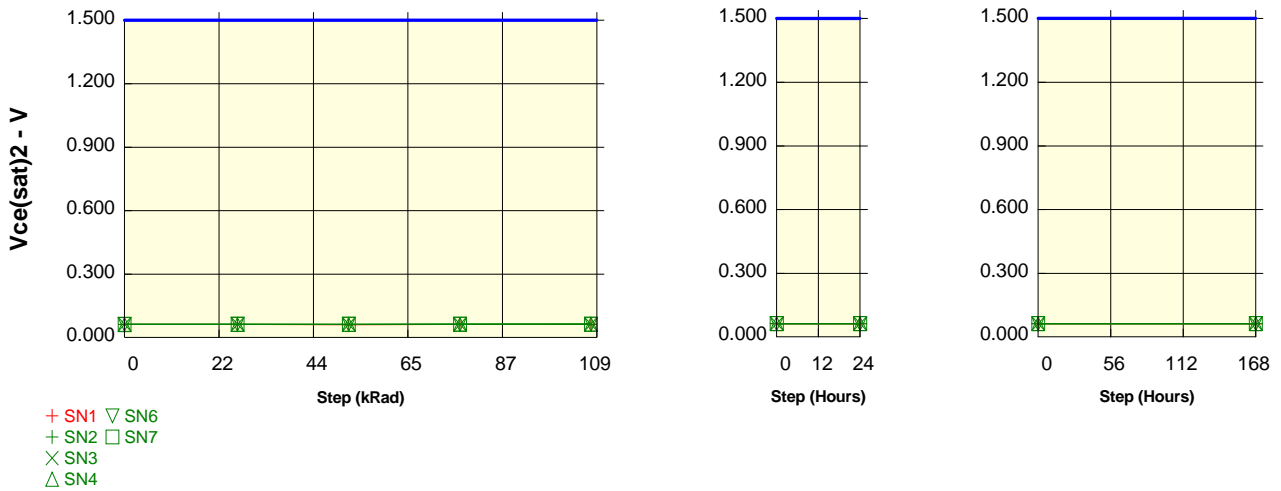
Measurements

Vce(sat)1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.035	0.034	0.034	0.035	0.035	0.034	0.035
On samples							
SN2	0.035	0.035	0.035	0.035	0.036	0.036	0.036
SN3	0.035	0.035	0.035	0.036	0.036	0.036	0.036
SN4	0.035	0.035	0.035	0.035	0.036	0.035	0.036
SN6	0.035	0.035	0.035	0.036	0.036	0.036	0.036
SN7	0.035	0.035	0.036	0.036	0.036	0.036	0.036
Statistics							
Min	0.035	0.035	0.035	0.035	0.036	0.035	0.036
Max	0.035	0.035	0.036	0.036	0.036	0.036	0.036
Average	0.035	0.035	0.035	0.036	0.036	0.036	0.036
Sigma	0.000	0.000	0.000	0.000	0.000	0.000	0.000
(Vce) Lot WorstCase	0.036	0.036	0.036	0.036	0.036	0.036	0.036

Drift Calculation

Vce(sat)1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	80.00E-06	-240.00E-06	160.00E-06	640.00E-06	920.00E-06	880.00E-06
SN3	-	200.00E-06	160.00E-06	520.00E-06	600.00E-06	800.00E-06	560.00E-06
SN4	-	640.00E-06	640.00E-06	840.00E-06	1.16E-03	840.00E-06	1000.00E-06
SN6	-	480.00E-06	520.00E-06	680.00E-06	880.00E-06	840.00E-06	760.00E-06
SN7	-	200.00E-06	280.00E-06	600.00E-06	720.00E-06	720.00E-06	680.00E-06
Average	-	320.00E-06	272.00E-06	560.00E-06	800.00E-06	824.00E-06	776.00E-06
Sigma	-	207.08E-06	307.14E-06	226.27E-06	203.96E-06	64.99E-06	153.05E-06
d(Vce) Lot WorstCase	-	941.23E-06	1.19E-03	1.24E-03	1.41E-03	1.02E-03	1.24E-03

Test conditions : TID
Parameter : Collector- Emitter Saturation Voltage : Vce(sat)2
Ic = 2A Ib = 200mA
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



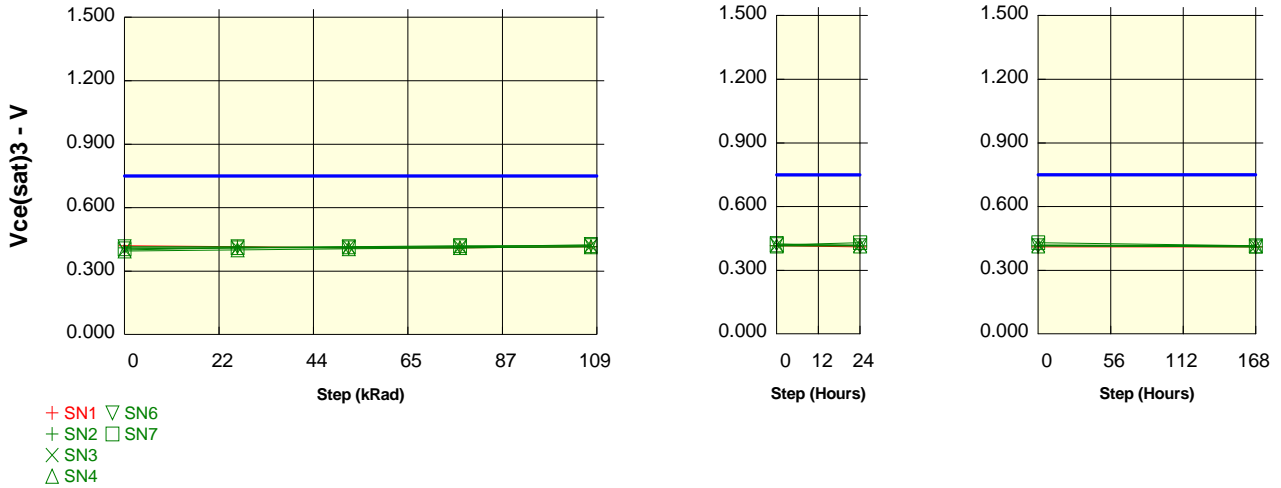
Measurements

Vce(sat)2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.062	0.061	0.061	0.061	0.061	0.061	0.062
On samples							
SN2	0.062	0.062	0.061	0.062	0.062	0.063	0.063
SN3	0.062	0.062	0.062	0.063	0.063	0.063	0.063
SN4	0.061	0.062	0.062	0.062	0.062	0.062	0.062
SN6	0.062	0.062	0.062	0.062	0.063	0.063	0.063
SN7	0.063	0.062	0.063	0.063	0.063	0.063	0.063
Statistics							
Min	0.061	0.062	0.061	0.062	0.062	0.062	0.062
Max	0.063	0.062	0.063	0.063	0.063	0.063	0.063
Average	0.062	0.062	0.062	0.062	0.063	0.063	0.063
Sigma	0.000	0.000	0.001	0.001	0.000	0.000	0.000
(Vce) Lot WorstCase	0.063	0.063	0.064	0.064	0.063	0.064	0.064

Drift Calculation

Vce(sat)2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	-120.00E-06	-760.00E-06	-200.00E-06	640.00E-06	960.00E-06	1000.00E-06
SN3	-	0.00E+00	-200.00E-06	200.00E-06	400.00E-06	720.00E-06	360.00E-06
SN4	-	680.00E-06	600.00E-06	680.00E-06	1000.00E-06	720.00E-06	920.00E-06
SN6	-	280.00E-06	320.00E-06	520.00E-06	680.00E-06	640.00E-06	680.00E-06
SN7	-	-200.00E-06	0.00E+00	440.00E-06	440.00E-06	600.00E-06	520.01E-06
Average	-	128.00E-06	-8.00E-06	328.00E-06	632.00E-06	728.00E-06	696.00E-06
Sigma	-	320.40E-06	464.69E-06	306.10E-06	213.77E-06	124.96E-06	239.46E-06
d(Vce) Lot WorstCase	-	1.09E-03	1.39E-03	1.25E-03	1.27E-03	1.10E-03	1.41E-03

Test conditions : TID
Parameter : Collector- Emitter Saturation Voltage : Vce(sat)3
Ic = 15A Ib = 1.2A
 Unit : V
 Spec Limit Max : 0.750
 Spec limits are represented in bold lines on the graphic.



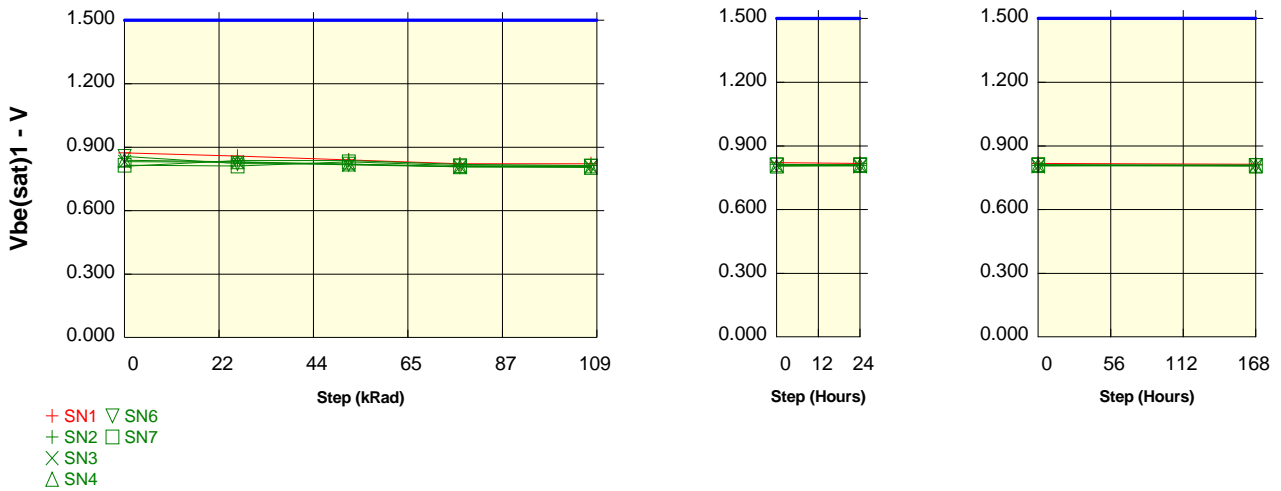
Measurements

Vce(sat)3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.420	0.415	0.410	0.410	0.415	0.410	0.410
On samples							
SN2	0.410	0.410	0.410	0.410	0.415	0.415	0.410
SN3	0.400	0.410	0.415	0.415	0.420	0.420	0.415
SN4	0.395	0.400	0.405	0.410	0.415	0.415	0.415
SN6	0.415	0.415	0.410	0.415	0.425	0.415	0.410
SN7	0.405	0.410	0.415	0.420	0.420	0.430	0.415
Statistics							
Min	0.395	0.400	0.405	0.410	0.415	0.415	0.410
Max	0.415	0.415	0.415	0.420	0.425	0.430	0.415
Average	0.405	0.409	0.411	0.414	0.419	0.419	0.413
Sigma	0.007	0.005	0.004	0.004	0.004	0.006	0.002
(Vce) Lot WorstCase	0.426	0.424	0.422	0.425	0.430	0.436	0.420

Drift Calculation

Vce(sat)3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	0.00E+00	0.00E+00	0.00E+00	5.00E-03	5.00E-03	0.00E+00
SN3	-	10.00E-03	15.00E-03	15.00E-03	20.00E-03	20.00E-03	15.00E-03
SN4	-	5.00E-03	10.00E-03	15.00E-03	20.00E-03	20.00E-03	20.00E-03
SN6	-	0.00E+00	-5.00E-03	0.00E+00	10.00E-03	0.00E+00	-5.00E-03
SN7	-	5.00E-03	10.00E-03	15.00E-03	15.00E-03	25.00E-03	10.00E-03
Average	-	4.00E-03	6.00E-03	9.00E-03	14.00E-03	14.00E-03	8.00E-03
Sigma	-	3.74E-03	7.35E-03	7.35E-03	5.83E-03	9.70E-03	9.27E-03
d(Vce) Lot WorstCase	-	15.22E-03	28.05E-03	31.05E-03	31.49E-03	43.09E-03	35.82E-03

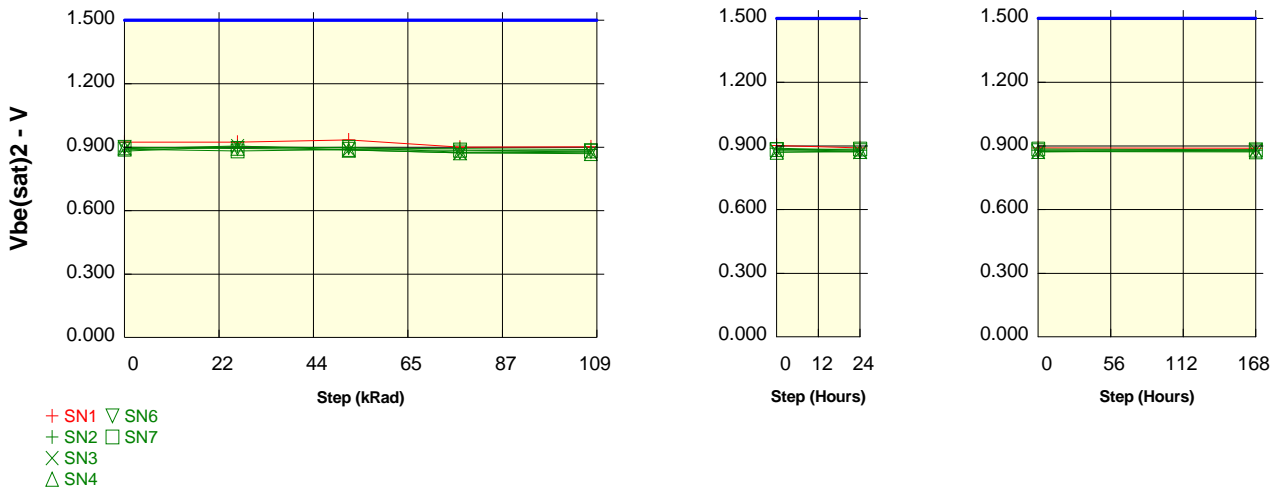
Test conditions : TID
Parameter : Base- Emitter Saturation Voltage : Vbe(sat)1
Ic = 1A Ib = 100mA
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



Measurements							
Vbe(sat)1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.873	0.857	0.839	0.821	0.822	0.817	0.814
On samples							
SN2	0.809	0.837	0.837	0.819	0.814	0.808	0.809
SN3	0.832	0.829	0.816	0.807	0.807	0.805	0.808
SN4	0.838	0.831	0.820	0.807	0.804	0.808	0.804
SN6	0.856	0.823	0.820	0.809	0.810	0.808	0.807
SN7	0.815	0.812	0.830	0.812	0.811	0.813	0.808
Statistics							
Min	0.809	0.812	0.816	0.807	0.804	0.805	0.804
Max	0.856	0.837	0.837	0.819	0.814	0.813	0.809
Average	0.830	0.826	0.825	0.811	0.809	0.808	0.807
Sigma	0.017	0.009	0.008	0.004	0.003	0.002	0.002
(Vbe) Lot WorstCase	0.881	0.852	0.848	0.824	0.819	0.815	0.813

Drift Calculation							
Vbe(sat)1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	27.68E-03	28.20E-03	9.68E-03	4.48E-03	-1.28E-03	40.00E-06
SN3	-	-2.52E-03	-15.92E-03	-24.56E-03	-24.92E-03	-26.64E-03	-23.44E-03
SN4	-	-7.64E-03	-18.12E-03	-31.28E-03	-34.24E-03	-30.64E-03	-34.12E-03
SN6	-	-33.68E-03	-36.56E-03	-47.68E-03	-46.24E-03	-47.88E-03	-49.52E-03
SN7	-	-3.36E-03	15.12E-03	-2.76E-03	-3.68E-03	-2.44E-03	-6.64E-03
Average	-	-3.90E-03	-5.46E-03	-19.32E-03	-20.92E-03	-21.78E-03	-22.74E-03
Sigma	-	19.50E-03	23.64E-03	20.45E-03	18.85E-03	17.76E-03	18.03E-03
d(Vbe) Lot WorstCase	-	54.58E-03	65.45E-03	42.02E-03	35.63E-03	31.51E-03	31.35E-03

Test conditions : TID
Parameter : Base- Emitter Saturation Voltage : Vbe(sat)2
Ic = 2A Ib = 200mA
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



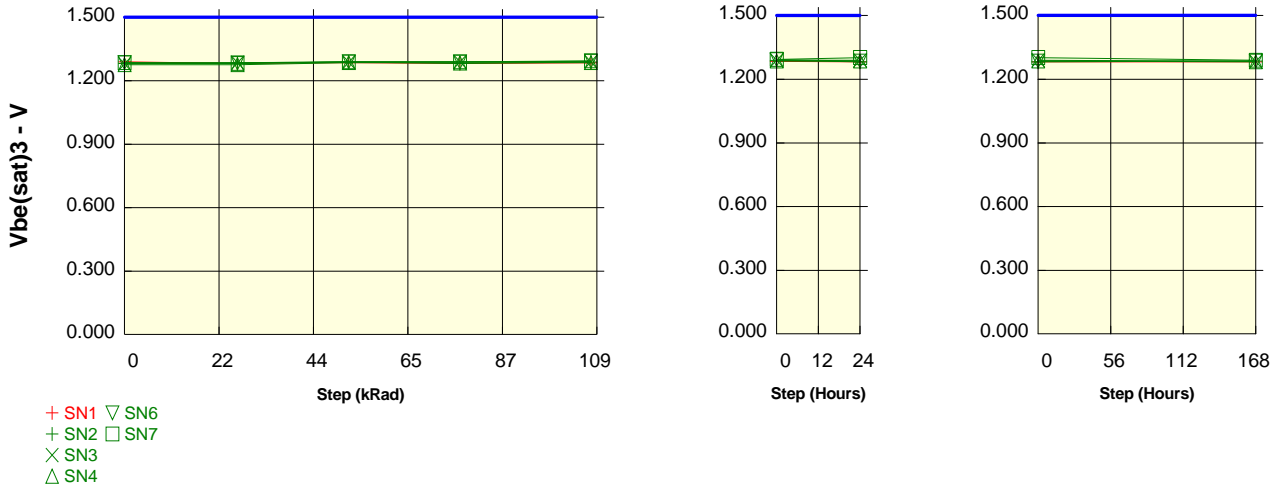
Measurements

Vbe(sat)2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.924	0.924	0.934	0.900	0.902	0.891	0.889
On samples							
SN2	0.881	0.903	0.896	0.893	0.889	0.880	0.880
SN3	0.894	0.905	0.888	0.873	0.875	0.872	0.881
SN4	0.897	0.894	0.886	0.874	0.870	0.873	0.872
SN6	0.899	0.894	0.899	0.876	0.881	0.877	0.875
SN7	0.891	0.882	0.890	0.886	0.883	0.885	0.881
Statistics							
Min	0.881	0.882	0.886	0.873	0.870	0.872	0.872
Max	0.899	0.905	0.899	0.893	0.889	0.885	0.881
Average	0.892	0.896	0.892	0.880	0.880	0.877	0.878
Sigma	0.006	0.008	0.005	0.008	0.006	0.005	0.004
(Vbe) Lot WorstCase	0.911	0.920	0.907	0.904	0.899	0.892	0.889

Drift Calculation

Vbe(sat)2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	21.80E-03	14.28E-03	11.44E-03	7.08E-03	-1.56E-03	-1.16E-03
SN3	-	11.80E-03	-5.84E-03	-20.76E-03	-18.16E-03	-21.60E-03	-12.64E-03
SN4	-	-3.60E-03	-11.56E-03	-23.88E-03	-27.40E-03	-24.04E-03	-25.36E-03
SN6	-	-4.84E-03	240.01E-06	-22.40E-03	-18.24E-03	-22.32E-03	-23.76E-03
SN7	-	-8.52E-03	-1.12E-03	-5.24E-03	-7.84E-03	-5.56E-03	-10.04E-03
Average	-	3.33E-03	-799.98E-06	-12.17E-03	-12.91E-03	-15.02E-03	-14.59E-03
Sigma	-	11.56E-03	8.60E-03	13.57E-03	11.76E-03	9.47E-03	9.00E-03
d(Vbe) Lot WorstCase	-	38.01E-03	25.00E-03	28.55E-03	22.36E-03	13.40E-03	12.41E-03

Test conditions : TID
Parameter : Base- Emitter Saturation Voltage : Vbe(sat)3
Ic = 15A Ib = 1.2A
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



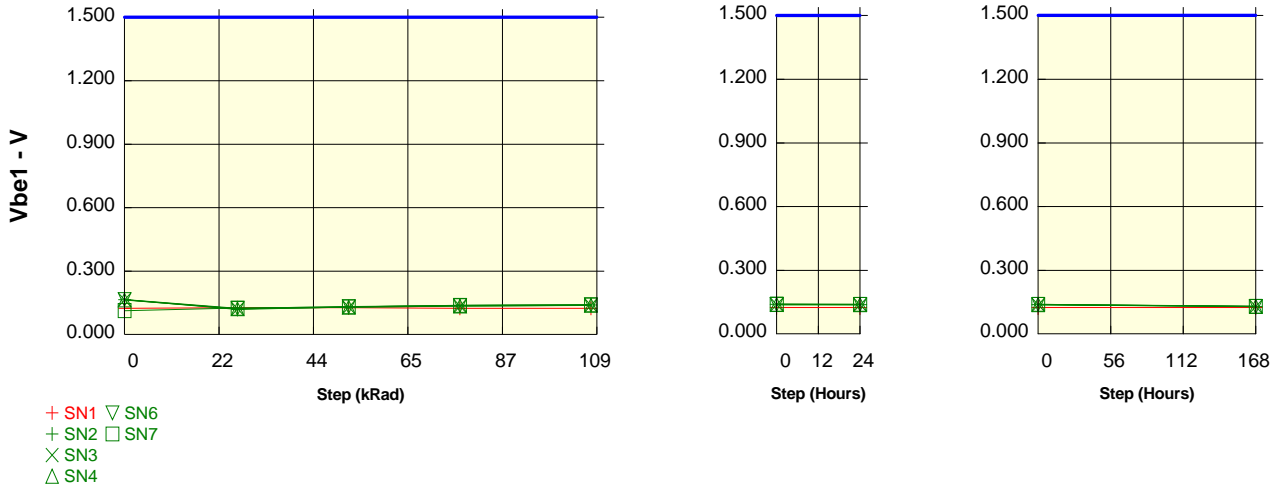
Measurements

Vbe(sat)3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	1.290	1.282	1.286	1.282	1.284	1.282	1.282
On samples							
SN2	1.282	1.282	1.288	1.282	1.288	1.282	1.286
SN3	1.280	1.286	1.288	1.290	1.290	1.290	1.284
SN4	1.276	1.276	1.286	1.284	1.286	1.286	1.282
SN6	1.286	1.284	1.290	1.288	1.292	1.286	1.286
SN7	1.286	1.282	1.290	1.290	1.294	1.302	1.290
Statistics							
Min	1.276	1.276	1.286	1.282	1.286	1.282	1.282
Max	1.286	1.286	1.290	1.290	1.294	1.302	1.290
Average	1.282	1.282	1.288	1.287	1.290	1.289	1.286
Sigma	0.004	0.003	0.001	0.003	0.003	0.007	0.003
(Vbe) Lot WorstCase	1.293	1.292	1.293	1.297	1.298	1.310	1.294

Drift Calculation

Vbe(sat)3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	26.23E-09	6.00E-03	0.00E+00	6.00E-03	0.00E+00	4.00E-03
SN3	-	6.00E-03	8.00E-03	10.00E-03	10.00E-03	10.00E-03	4.00E-03
SN4	-	-33.38E-09	10.00E-03	8.00E-03	10.00E-03	10.00E-03	6.00E-03
SN6	-	-2.00E-03	4.00E-03	2.00E-03	6.00E-03	0.00E+00	0.00E+00
SN7	-	-4.00E-03	4.00E-03	4.00E-03	8.00E-03	16.00E-03	4.00E-03
Average	-	-2.86E-09	6.40E-03	4.80E-03	8.00E-03	7.20E-03	3.60E-03
Sigma	-	3.35E-03	2.33E-03	3.71E-03	1.79E-03	6.27E-03	1.96E-03
d(Vbe) Lot WorstCase	-	10.04E-03	13.40E-03	15.93E-03	13.37E-03	26.02E-03	9.48E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe1
IC = 0.1 mA Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



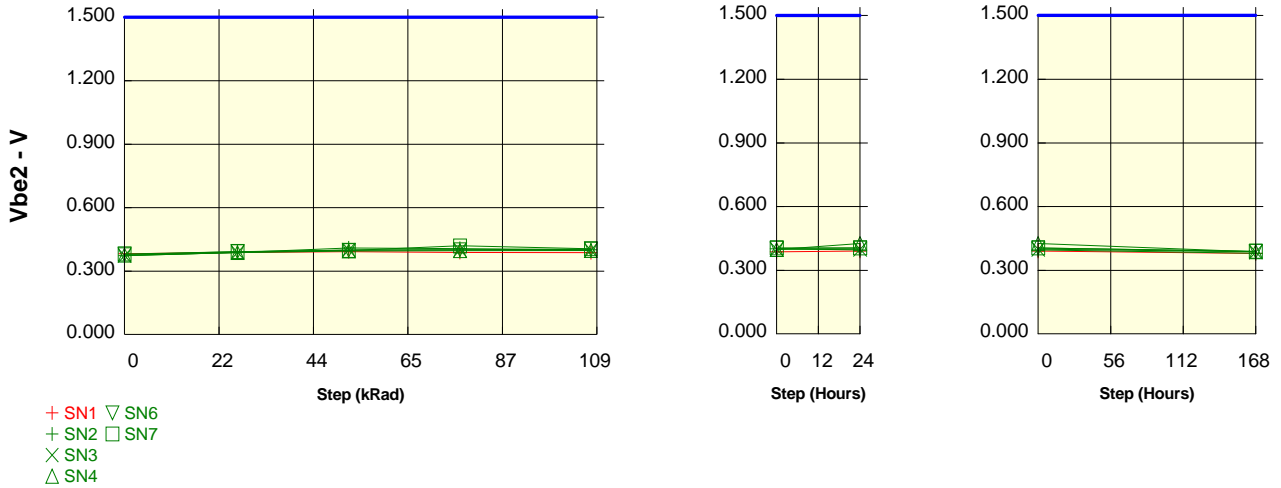
Measurements

Vbe1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.124	0.126	0.126	0.124	0.124	0.124	0.124
On samples							
SN2	0.164	0.120	0.131	0.137	0.139	0.138	0.129
SN3	0.164	0.122	0.129	0.134	0.138	0.137	0.128
SN4	0.163	0.122	0.129	0.135	0.138	0.138	0.130
SN6	0.166	0.124	0.132	0.137	0.139	0.140	0.129
SN7	0.113	0.125	0.131	0.138	0.141	0.139	0.131
Statistics							
Min	0.113	0.120	0.129	0.134	0.138	0.137	0.128
Max	0.166	0.125	0.132	0.138	0.141	0.140	0.131
Average	0.154	0.122	0.130	0.136	0.139	0.138	0.130
Sigma	0.021	0.002	0.001	0.001	0.001	0.001	0.001
(Vbe) Lot WorstCase	0.216	0.128	0.133	0.140	0.142	0.142	0.132

Drift Calculation

Vbe1	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	-44.72E-03	-33.48E-03	-27.64E-03	-24.84E-03	-26.00E-03	-34.88E-03
SN3	-	-42.04E-03	-34.64E-03	-29.44E-03	-26.08E-03	-26.84E-03	-35.44E-03
SN4	-	-41.40E-03	-34.16E-03	-28.32E-03	-25.08E-03	-25.38E-03	-32.96E-03
SN6	-	-41.72E-03	-34.44E-03	-28.84E-03	-26.68E-03	-26.16E-03	-37.24E-03
SN7	-	11.96E-03	17.80E-03	25.03E-03	27.80E-03	26.56E-03	17.84E-03
Average	-	-31.58E-03	-23.78E-03	-17.84E-03	-14.98E-03	-15.56E-03	-24.54E-03
Sigma	-	21.80E-03	20.80E-03	21.45E-03	21.40E-03	21.07E-03	21.23E-03
d(Vbe) Lot WorstCase	-	33.83E-03	38.60E-03	46.50E-03	49.22E-03	47.64E-03	39.16E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe2
IC = 1 mA Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



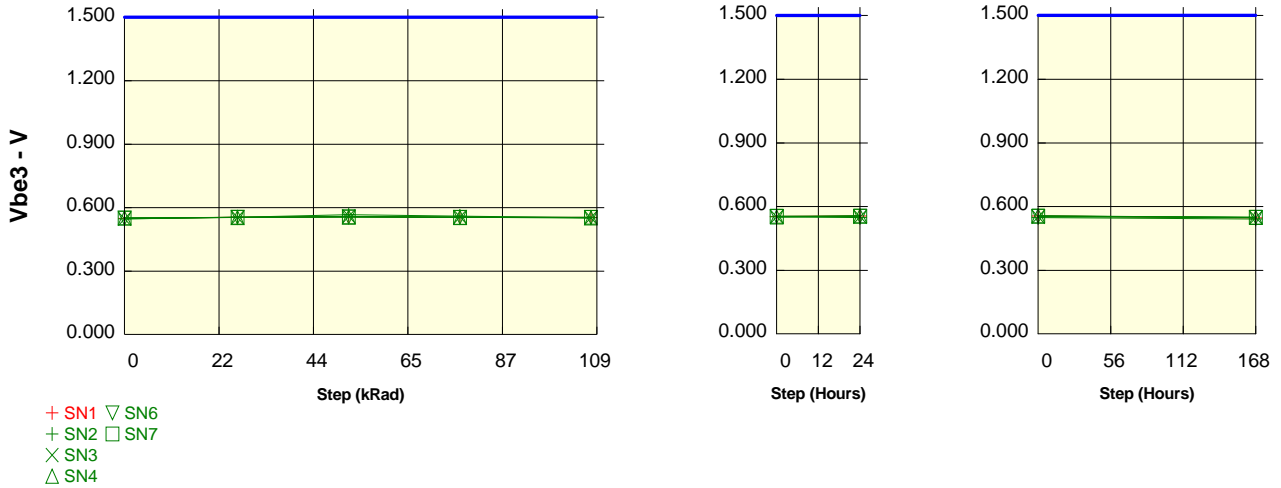
Measurements

Vbe2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.382	0.388	0.393	0.388	0.387	0.391	0.379
On samples							
SN2	0.373	0.389	0.410	0.407	0.401	0.396	0.380
SN3	0.373	0.388	0.400	0.400	0.399	0.399	0.387
SN4	0.376	0.387	0.395	0.397	0.397	0.425	0.387
SN6	0.378	0.392	0.398	0.401	0.403	0.406	0.389
SN7	0.381	0.392	0.397	0.419	0.406	0.405	0.390
Statistics							
Min	0.373	0.387	0.395	0.397	0.397	0.396	0.380
Max	0.381	0.392	0.410	0.419	0.406	0.425	0.390
Average	0.376	0.390	0.400	0.405	0.401	0.406	0.387
Sigma	0.003	0.002	0.005	0.008	0.003	0.010	0.003
(Vbe) Lot WorstCase	0.386	0.396	0.415	0.428	0.410	0.437	0.397

Drift Calculation

Vbe2	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	16.08E-03	37.04E-03	34.36E-03	28.20E-03	23.28E-03	7.48E-03
SN3	-	15.00E-03	27.08E-03	26.60E-03	25.88E-03	26.32E-03	13.44E-03
SN4	-	11.32E-03	19.28E-03	20.88E-03	21.52E-03	49.56E-03	11.68E-03
SN6	-	14.24E-03	20.24E-03	22.92E-03	25.12E-03	27.52E-03	10.48E-03
SN7	-	11.52E-03	16.36E-03	37.88E-03	24.80E-03	23.84E-03	9.16E-03
Average	-	13.63E-03	24.00E-03	28.53E-03	25.10E-03	30.10E-03	10.45E-03
Sigma	-	1.90E-03	7.41E-03	6.56E-03	2.15E-03	9.85E-03	2.05E-03
d(Vbe) Lot WorstCase	-	19.33E-03	46.22E-03	48.21E-03	31.56E-03	59.66E-03	16.59E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe3
IC = 10 mA Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



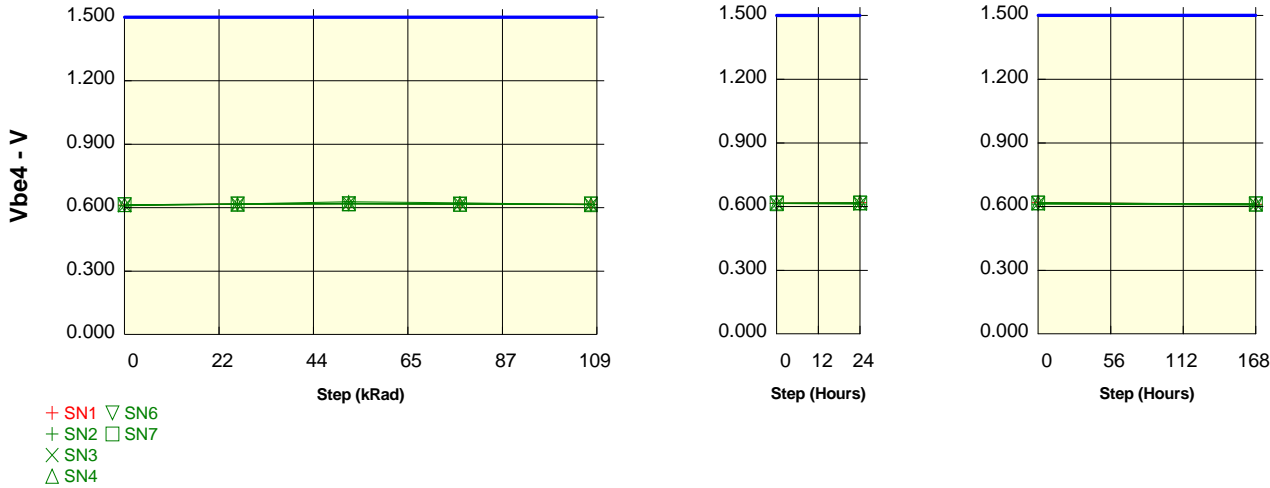
Measurements

Vbe3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.549	0.554	0.558	0.554	0.553	0.556	0.548
On samples							
SN2	0.546	0.555	0.566	0.560	0.552	0.548	0.542
SN3	0.547	0.553	0.559	0.556	0.552	0.552	0.548
SN4	0.552	0.553	0.556	0.554	0.551	0.557	0.549
SN6	0.550	0.555	0.556	0.555	0.554	0.555	0.550
SN7	0.551	0.555	0.555	0.553	0.555	0.555	0.549
Statistics							
Min	0.546	0.553	0.555	0.553	0.551	0.548	0.542
Max	0.552	0.555	0.566	0.560	0.555	0.557	0.550
Average	0.549	0.554	0.558	0.556	0.553	0.553	0.548
Sigma	0.002	0.001	0.004	0.003	0.001	0.003	0.003
(Vbe) Lot WorstCase	0.555	0.557	0.571	0.563	0.557	0.562	0.556

Drift Calculation

Vbe3	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	8.08E-03	19.72E-03	13.92E-03	5.84E-03	2.04E-03	-4.28E-03
SN3	-	5.56E-03	11.76E-03	8.80E-03	4.76E-03	4.88E-03	1.12E-03
SN4	-	1.28E-03	4.40E-03	2.76E-03	-239.97E-06	5.32E-03	-2.76E-03
SN6	-	4.80E-03	5.96E-03	5.04E-03	3.76E-03	5.00E-03	-480.00E-06
SN7	-	3.96E-03	4.68E-03	2.20E-03	4.00E-03	4.00E-03	-1.28E-03
Average	-	4.74E-03	9.30E-03	6.54E-03	3.62E-03	4.25E-03	-1.54E-03
Sigma	-	2.21E-03	5.85E-03	4.36E-03	2.06E-03	1.19E-03	1.86E-03
d(Vbe) Lot WorstCase	-	11.36E-03	26.86E-03	19.62E-03	9.81E-03	7.81E-03	4.04E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe4
IC = 0.1 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



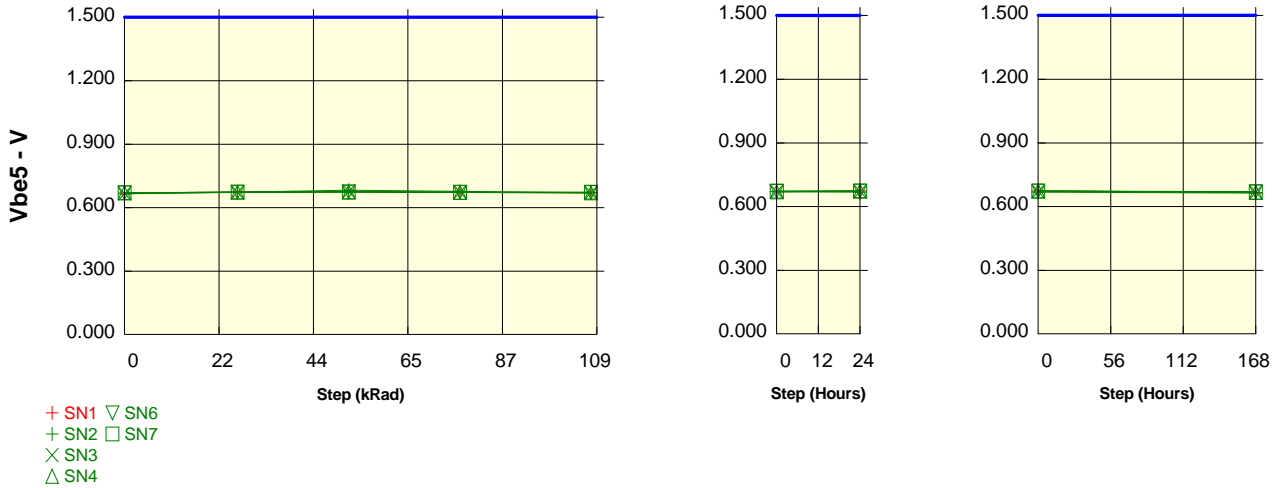
Measurements

Vbe4	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.612	0.617	0.620	0.617	0.615	0.618	0.611
On samples							
SN2	0.610	0.617	0.627	0.622	0.615	0.612	0.606
SN3	0.610	0.616	0.621	0.618	0.615	0.615	0.611
SN4	0.614	0.616	0.618	0.617	0.614	0.619	0.612
SN6	0.613	0.617	0.618	0.617	0.616	0.617	0.613
SN7	0.614	0.617	0.618	0.616	0.617	0.617	0.612
Statistics							
Min	0.610	0.616	0.618	0.616	0.614	0.612	0.606
Max	0.614	0.617	0.627	0.622	0.617	0.619	0.613
Average	0.612	0.617	0.621	0.618	0.615	0.616	0.611
Sigma	0.002	0.001	0.004	0.002	0.001	0.003	0.002
(Vbe) Lot WorstCase	0.618	0.619	0.631	0.625	0.619	0.624	0.618

Drift Calculation

Vbe4	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	7.40E-03	17.68E-03	12.48E-03	5.36E-03	2.16E-03	-3.40E-03
SN3	-	5.16E-03	10.60E-03	7.84E-03	4.20E-03	4.76E-03	920.00E-06
SN4	-	1.28E-03	4.00E-03	2.32E-03	-399.95E-06	4.68E-03	-2.76E-03
SN6	-	4.12E-03	5.24E-03	4.28E-03	3.32E-03	4.32E-03	-400.01E-06
SN7	-	3.52E-03	4.24E-03	2.00E-03	3.56E-03	3.60E-03	-1.28E-03
Average	-	4.30E-03	8.35E-03	5.78E-03	3.21E-03	3.90E-03	-1.38E-03
Sigma	-	2.01E-03	5.25E-03	3.94E-03	1.94E-03	963.52E-06	1.56E-03
d(Vbe) Lot WorstCase	-	10.31E-03	24.09E-03	17.61E-03	9.02E-03	6.79E-03	3.31E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe5
IC = 0.5 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



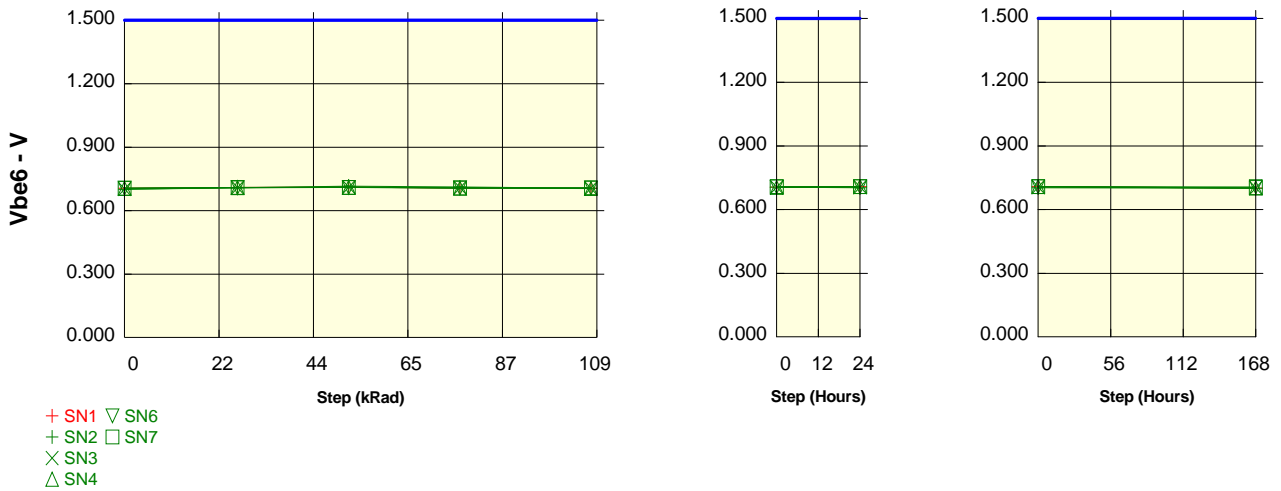
Measurements

Vbe5	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.669	0.673	0.676	0.672	0.671	0.673	0.667
On samples							
SN2	0.666	0.673	0.682	0.677	0.671	0.668	0.664
SN3	0.667	0.672	0.676	0.674	0.670	0.671	0.667
SN4	0.670	0.673	0.675	0.672	0.669	0.674	0.667
SN6	0.670	0.673	0.674	0.673	0.672	0.673	0.670
SN7	0.670	0.673	0.674	0.672	0.673	0.673	0.668
Statistics							
Min	0.666	0.672	0.674	0.672	0.669	0.668	0.664
Max	0.670	0.673	0.682	0.677	0.673	0.674	0.670
Average	0.668	0.673	0.676	0.673	0.671	0.672	0.667
Sigma	0.002	0.000	0.003	0.002	0.001	0.002	0.002
(Vbe) Lot WorstCase	0.674	0.674	0.685	0.679	0.675	0.678	0.674

Drift Calculation

Vbe5	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	7.52E-03	16.36E-03	11.56E-03	5.08E-03	2.52E-03	-1.92E-03
SN3	-	5.60E-03	9.36E-03	6.92E-03	3.56E-03	4.32E-03	519.99E-06
SN4	-	2.68E-03	4.36E-03	1.72E-03	-760.02E-06	3.96E-03	-3.04E-03
SN6	-	3.48E-03	4.48E-03	3.00E-03	2.20E-03	3.08E-03	320.02E-06
SN7	-	3.28E-03	4.24E-03	2.00E-03	3.36E-03	3.32E-03	-1.32E-03
Average	-	4.51E-03	7.76E-03	5.04E-03	2.69E-03	3.44E-03	-1.09E-03
Sigma	-	1.80E-03	4.72E-03	3.75E-03	1.95E-03	637.98E-06	1.35E-03
d(Vbe) Lot WorstCase	-	9.91E-03	21.91E-03	16.30E-03	8.55E-03	5.35E-03	2.96E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe6
IC = 1 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



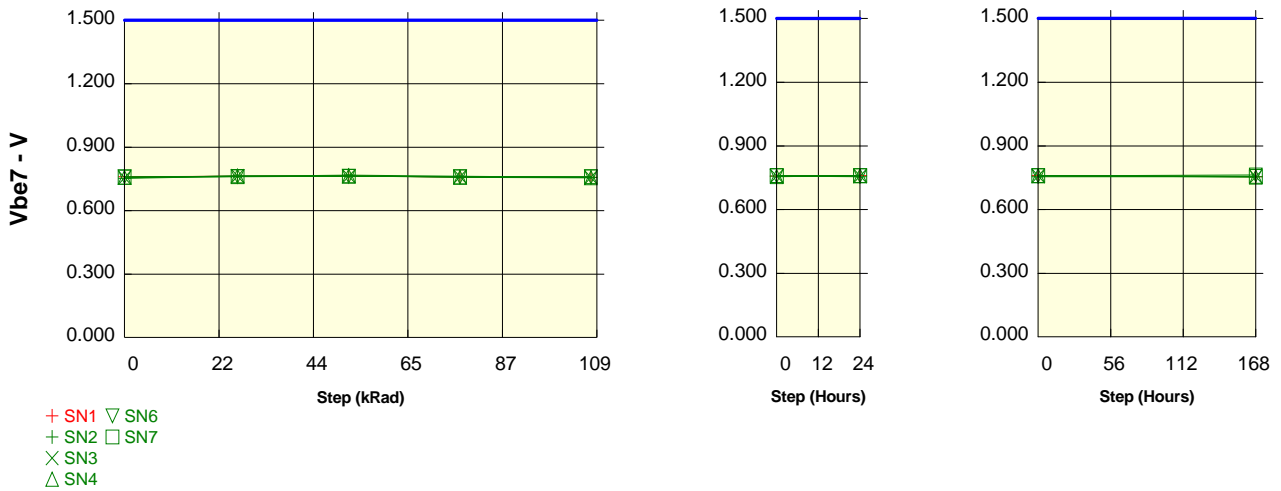
Measurements

Vbe6	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.705	0.709	0.711	0.707	0.706	0.708	0.702
On samples							
SN2	0.701	0.709	0.716	0.712	0.706	0.703	0.700
SN3	0.702	0.709	0.711	0.708	0.705	0.706	0.702
SN4	0.705	0.709	0.710	0.706	0.704	0.709	0.702
SN6	0.706	0.709	0.710	0.708	0.707	0.708	0.707
SN7	0.705	0.708	0.710	0.707	0.708	0.708	0.704
Statistics							
Min	0.701	0.708	0.710	0.706	0.704	0.703	0.700
Max	0.706	0.709	0.716	0.712	0.708	0.709	0.707
Average	0.704	0.709	0.711	0.708	0.706	0.707	0.703
Sigma	0.002	0.000	0.003	0.002	0.001	0.002	0.002
(Vbe) Lot WorstCase	0.710	0.710	0.719	0.714	0.710	0.713	0.710

Drift Calculation

Vbe6	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	8.08E-03	15.80E-03	11.00E-03	5.04E-03	2.76E-03	-280.02E-06
SN3	-	6.44E-03	8.52E-03	6.12E-03	3.00E-03	4.00E-03	-79.99E-06
SN4	-	3.96E-03	4.88E-03	959.99E-06	-1.36E-03	3.12E-03	-3.68E-03
SN6	-	3.12E-03	3.76E-03	1.72E-03	1.20E-03	1.84E-03	1.40E-03
SN7	-	2.84E-03	4.40E-03	1.88E-03	3.08E-03	3.08E-03	-1.52E-03
Average	-	4.89E-03	7.47E-03	4.34E-03	2.19E-03	2.96E-03	-832.00E-06
Sigma	-	2.04E-03	4.48E-03	3.79E-03	2.15E-03	695.11E-06	1.70E-03
d(Vbe) Lot WorstCase	-	11.00E-03	20.91E-03	15.71E-03	8.65E-03	5.05E-03	4.27E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe7
IC = 2 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



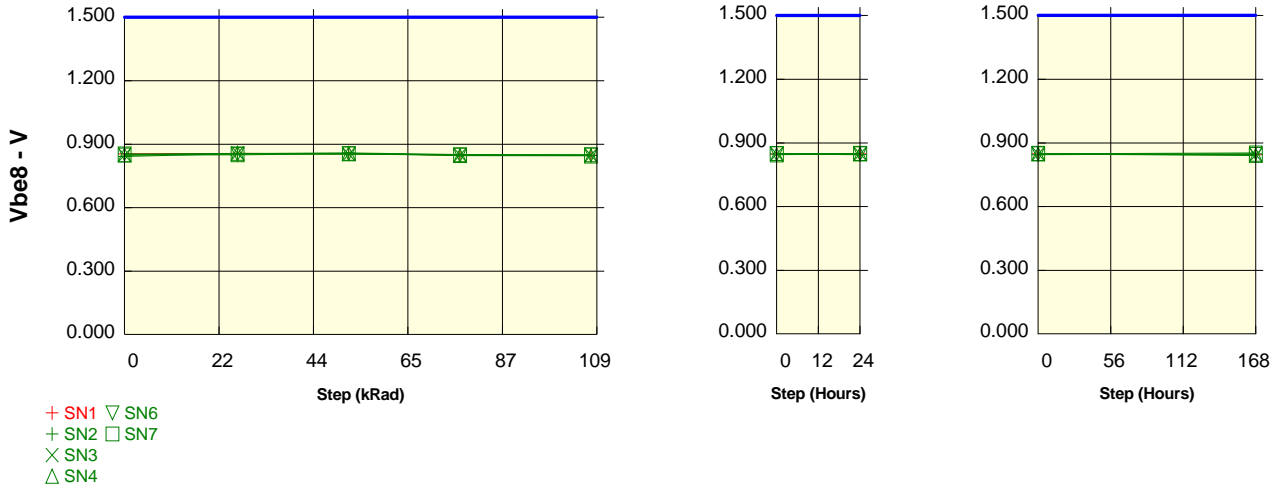
Measurements

Vbe7	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.760	0.763	0.764	0.759	0.758	0.760	0.755
On samples							
SN2	0.753	0.761	0.769	0.763	0.758	0.756	0.755
SN3	0.756	0.764	0.763	0.760	0.757	0.758	0.755
SN4	0.758	0.764	0.764	0.758	0.756	0.760	0.753
SN6	0.760	0.762	0.763	0.760	0.760	0.759	0.763
SN7	0.758	0.761	0.763	0.760	0.760	0.760	0.756
Statistics							
Min	0.753	0.761	0.763	0.758	0.756	0.756	0.753
Max	0.760	0.764	0.769	0.763	0.760	0.760	0.763
Average	0.757	0.762	0.764	0.760	0.758	0.759	0.757
Sigma	0.003	0.001	0.002	0.002	0.002	0.002	0.003
(Vbe) Lot WorstCase	0.765	0.767	0.771	0.765	0.763	0.764	0.767

Drift Calculation

Vbe7	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	8.80E-03	16.12E-03	10.60E-03	5.24E-03	3.04E-03	2.92E-03
SN3	-	8.16E-03	7.60E-03	4.48E-03	1.84E-03	2.72E-03	-839.95E-06
SN4	-	6.32E-03	6.32E-03	-320.02E-06	-2.48E-03	1.64E-03	-4.76E-03
SN6	-	1.20E-03	2.76E-03	-800.01E-06	-880.00E-06	-920.00E-06	2.72E-03
SN7	-	2.40E-03	4.76E-03	1.60E-03	2.20E-03	2.20E-03	-1.72E-03
Average	-	5.38E-03	7.51E-03	3.11E-03	1.18E-03	1.74E-03	-336.00E-06
Sigma	-	3.05E-03	4.60E-03	4.18E-03	2.67E-03	1.41E-03	2.89E-03
d(Vbe) Lot WorstCase	-	14.54E-03	21.30E-03	15.65E-03	9.19E-03	5.97E-03	8.33E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe8
IC = 4 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



+ SN1 ▽ SN6
 + SN2 □ SN7
 X SN3
 △ SN4

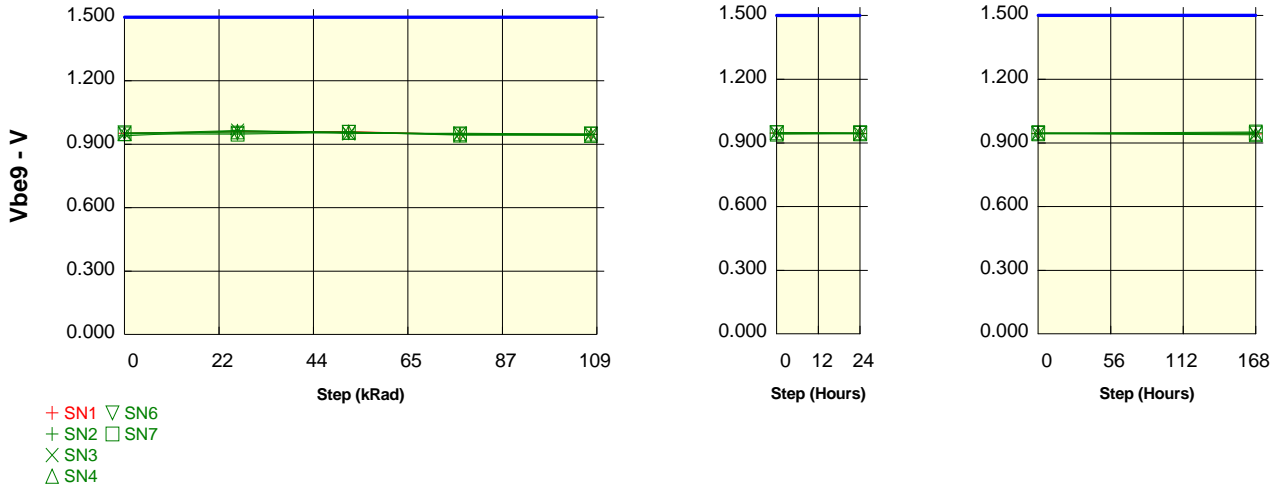
Measurements

Vbe8	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.853	0.856	0.856	0.848	0.848	0.849	0.844
On samples							
SN2	0.842	0.856	0.859	0.851	0.848	0.845	0.848
SN3	0.848	0.857	0.853	0.849	0.848	0.848	0.844
SN4	0.849	0.857	0.857	0.846	0.844	0.847	0.841
SN6	0.854	0.853	0.855	0.848	0.849	0.848	0.852
SN7	0.849	0.850	0.855	0.850	0.850	0.850	0.846
Statistics							
Min	0.842	0.850	0.853	0.846	0.844	0.845	0.841
Max	0.854	0.857	0.859	0.851	0.850	0.850	0.852
Average	0.849	0.855	0.856	0.849	0.848	0.848	0.846
Sigma	0.004	0.003	0.002	0.002	0.002	0.002	0.004
(Vbe) Lot WorstCase	0.860	0.862	0.862	0.855	0.854	0.853	0.858

Drift Calculation

Vbe8	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	13.40E-03	16.68E-03	9.16E-03	5.56E-03	3.20E-03	6.24E-03
SN3	-	8.44E-03	4.44E-03	840.01E-06	-639.98E-06	-480.00E-06	-4.76E-03
SN4	-	7.48E-03	7.08E-03	-3.56E-03	-5.16E-03	-2.08E-03	-8.04E-03
SN6	-	-760.02E-06	1.40E-03	-5.48E-03	-4.56E-03	-5.32E-03	-1.32E-03
SN7	-	1.44E-03	5.68E-03	1.12E-03	1.20E-03	1.40E-03	-2.80E-03
Average	-	6.00E-03	7.06E-03	416.03E-06	-719.98E-06	-656.00E-06	-2.14E-03
Sigma	-	5.09E-03	5.16E-03	5.05E-03	3.94E-03	2.93E-03	4.75E-03
d(Vbe) Lot WorstCase	-	21.26E-03	22.55E-03	15.58E-03	11.10E-03	8.13E-03	12.13E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe9
IC = 6 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



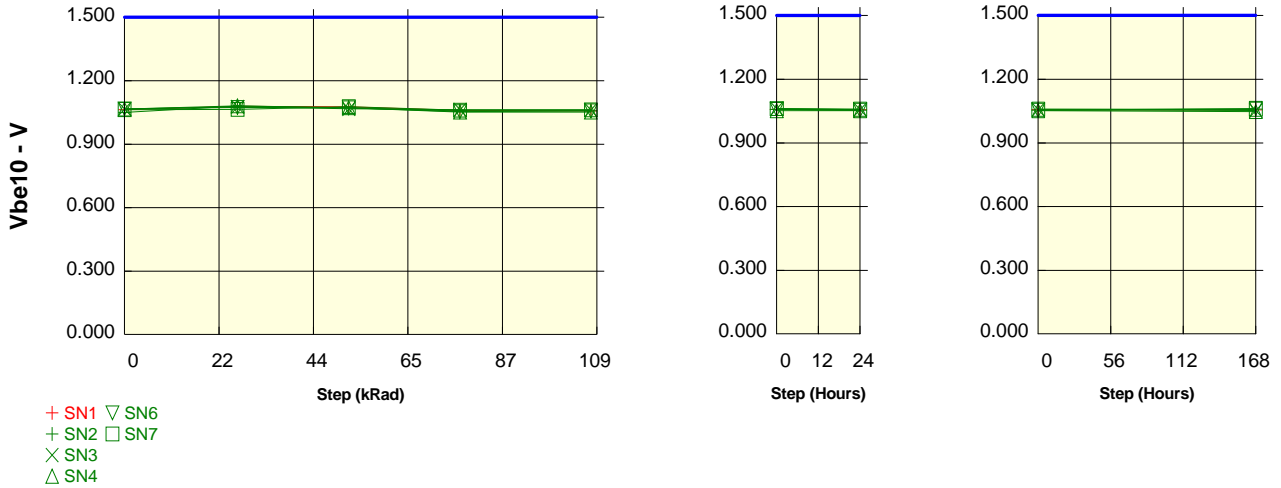
Measurements

Vbe9	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	0.951	0.960	0.959	0.947	0.946	0.945	0.943
On samples							
SN2	0.940	0.963	0.957	0.948	0.946	0.943	0.947
SN3	0.950	0.964	0.950	0.952	0.948	0.945	0.942
SN4	0.950	0.959	0.956	0.942	0.941	0.943	0.938
SN6	0.954	0.953	0.956	0.945	0.947	0.945	0.951
SN7	0.949	0.948	0.956	0.949	0.948	0.948	0.945
Statistics							
Min	0.940	0.948	0.950	0.942	0.941	0.943	0.938
Max	0.954	0.964	0.957	0.952	0.948	0.948	0.951
Average	0.949	0.957	0.955	0.947	0.946	0.945	0.945
Sigma	0.005	0.006	0.003	0.003	0.003	0.002	0.005
(Vbe) Lot WorstCase	0.963	0.975	0.963	0.957	0.954	0.950	0.958

Drift Calculation

Vbe9	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	22.88E-03	17.44E-03	7.72E-03	6.28E-03	3.52E-03	7.24E-03
SN3	-	13.68E-03	-159.98E-06	1.28E-03	-2.36E-03	-4.92E-03	-8.56E-03
SN4	-	8.36E-03	6.24E-03	-7.96E-03	-9.00E-03	-7.04E-03	-12.08E-03
SN6	-	-760.02E-06	2.24E-03	-9.20E-03	-6.44E-03	-9.04E-03	-2.36E-03
SN7	-	-1.24E-03	7.16E-03	-519.99E-06	-1.20E-03	-1.04E-03	-3.80E-03
Average	-	8.58E-03	6.58E-03	-1.74E-03	-2.54E-03	-3.70E-03	-3.91E-03
Sigma	-	9.10E-03	6.04E-03	6.24E-03	5.23E-03	4.48E-03	6.56E-03
d(Vbe) Lot WorstCase	-	35.89E-03	24.72E-03	16.97E-03	13.13E-03	9.74E-03	15.77E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe10
IC = 8 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.500
 Spec limits are represented in bold lines on the graphic.



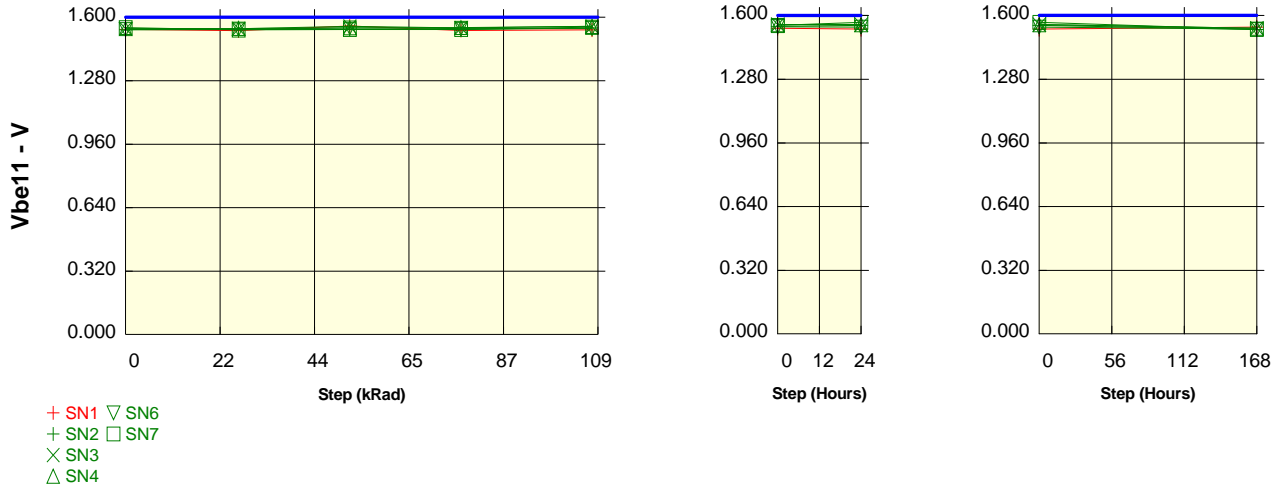
Measurements

Vbe10	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	1.063	1.079	1.076	1.059	1.058	1.057	1.056
On samples							
SN2	1.051	1.080	1.072	1.057	1.059	1.055	1.059
SN3	1.066	1.076	1.067	1.063	1.062	1.057	1.053
SN4	1.066	1.082	1.072	1.052	1.052	1.052	1.048
SN6	1.068	1.074	1.072	1.054	1.058	1.054	1.062
SN7	1.064	1.065	1.078	1.061	1.062	1.059	1.059
Statistics							
Min	1.051	1.065	1.067	1.052	1.052	1.052	1.048
Max	1.068	1.082	1.078	1.063	1.062	1.059	1.062
Average	1.063	1.075	1.072	1.057	1.058	1.055	1.056
Sigma	0.006	0.006	0.003	0.004	0.004	0.002	0.005
(Vbe) Lot WorstCase	1.081	1.093	1.082	1.070	1.069	1.062	1.072

Drift Calculation

Vbe10	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	28.96E-03	21.36E-03	6.36E-03	7.84E-03	3.96E-03	8.20E-03
SN3	-	10.32E-03	880.00E-06	-2.84E-03	-4.28E-03	-9.04E-03	-13.16E-03
SN4	-	15.64E-03	6.24E-03	-14.40E-03	-14.60E-03	-14.24E-03	-18.24E-03
SN6	-	5.96E-03	4.28E-03	-13.80E-03	-9.80E-03	-13.84E-03	-5.08E-03
SN7	-	1.16E-03	13.84E-03	-3.00E-03	-2.00E-03	-4.96E-03	-5.00E-03
Average	-	12.41E-03	9.32E-03	-5.54E-03	-4.57E-03	-7.62E-03	-6.66E-03
Sigma	-	9.56E-03	7.37E-03	7.77E-03	7.60E-03	6.72E-03	8.97E-03
d(Vbe) Lot WorstCase	-	41.08E-03	31.43E-03	17.78E-03	18.23E-03	12.53E-03	20.26E-03

Test conditions : TID
Parameter : Base – Emitter Voltage : Vbe11
IC = 15 A Vce = 2 V
 Unit : V
 Spec Limit Max : 1.600
 Spec limits are represented in bold lines on the graphic.



Measurements

Vbe11	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
SN1_REF	1.540	1.532	1.556	1.534	1.536	1.532	1.542
On samples							
SN2	1.536	1.538	1.540	1.538	1.546	1.550	1.530
SN3	1.542	1.542	1.554	1.546	1.554	1.554	1.536
SN4	1.542	1.544	1.546	1.548	1.554	1.554	1.536
SN6	1.538	1.540	1.546	1.544	1.544	1.542	1.532
SN7	1.548	1.536	1.538	1.538	1.550	1.566	1.530
Statistics							
Min	1.536	1.536	1.538	1.538	1.544	1.542	1.530
Max	1.548	1.544	1.554	1.548	1.554	1.566	1.536
Average	1.541	1.540	1.545	1.543	1.550	1.553	1.533
Sigma	0.004	0.003	0.006	0.004	0.004	0.008	0.003
(Vbe) Lot WorstCase	1.554	1.548	1.562	1.555	1.562	1.576	1.541

Drift Calculation

Vbe11	0 kRad	26.3 kRad	52.2 kRad	78.1 kRad	108.6 kRad	24 Hours	168 Hours
On samples							
SN2	-	2.00E-03	4.00E-03	2.00E-03	10.00E-03	14.00E-03	-6.00E-03
SN3	-	0.00E+00	12.00E-03	4.00E-03	12.00E-03	12.00E-03	-6.00E-03
SN4	-	2.00E-03	4.00E-03	6.00E-03	12.00E-03	12.00E-03	-6.00E-03
SN6	-	2.00E-03	8.00E-03	6.00E-03	6.00E-03	4.00E-03	-6.00E-03
SN7	-	-12.00E-03	-10.00E-03	-10.00E-03	2.00E-03	18.00E-03	-18.00E-03
Average	-	-1.20E-03	3.60E-03	1.60E-03	8.40E-03	12.00E-03	-8.40E-03
Sigma	-	5.46E-03	7.42E-03	5.99E-03	3.88E-03	4.56E-03	4.80E-03
d(Vbe) Lot WorstCase	-	15.17E-03	25.86E-03	19.56E-03	20.03E-03	25.68E-03	6.00E-03